

JEITA's Standardization Activity of 2nd Generation Lead-Free Solder Paste

**JEITA 2nd Generation Lead-Free Reflow
Solder Paste Standardization Project Group**

**JEITA PG Leader
Koji Serizawa**

Committee Members

Leader : Koji Serizawa

Sub-leader : Kenichi Tomitsuka



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Panasonic



Toshiba

Henkel Japan

NEC



KOA株式会社

KOA CORPORATION



エレクトロニクス時代を支える

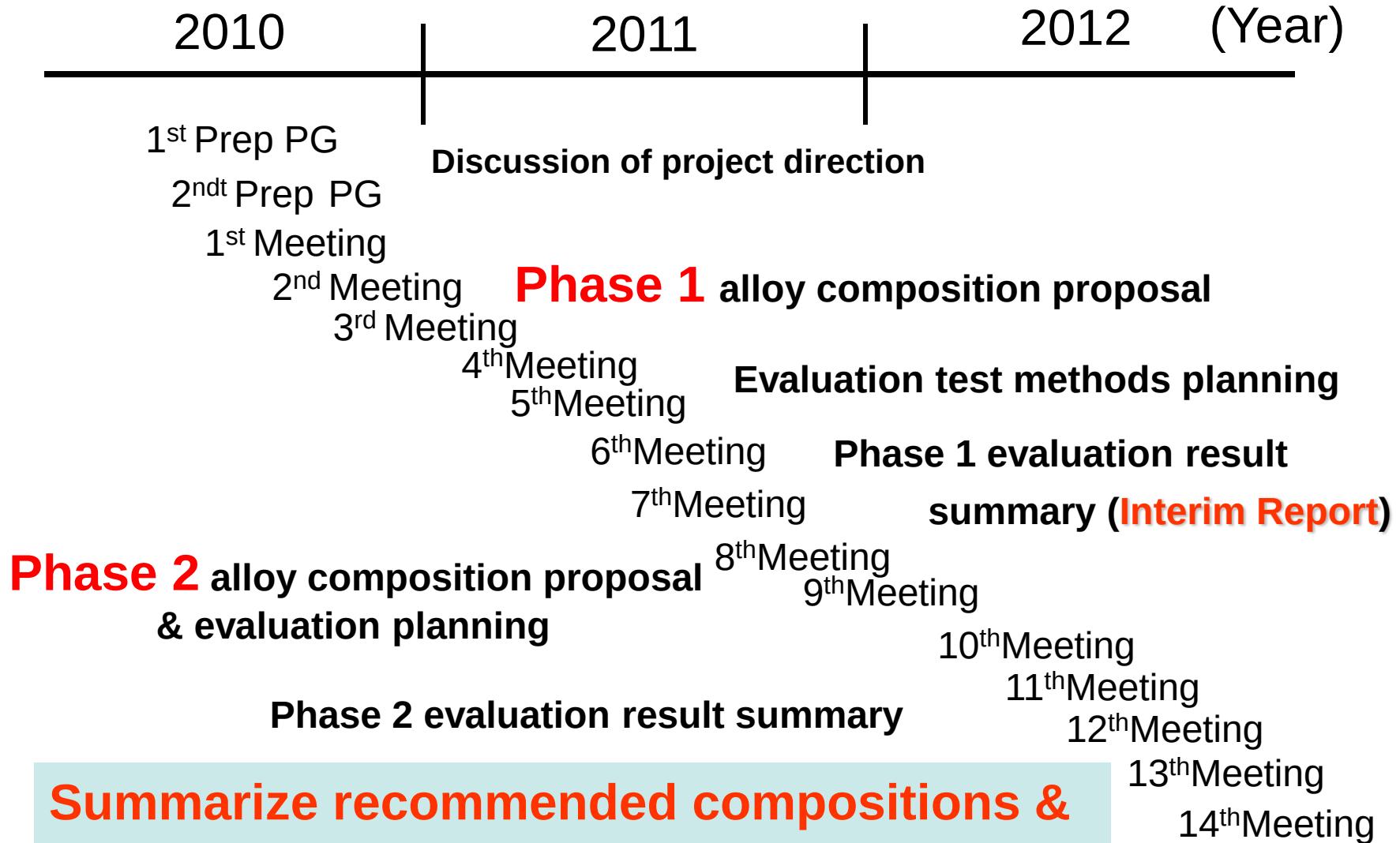
株式会社 ニホンゲンマ



HITACHI
Inspire the Next



Project Activities



Project Action Plans

1. Obtain suggestions from the solder manufactures



Low-Ag SAC Paste

- Increase in reflow temp
- Impact on thermal fatigue and wetting



- Lower temp by adding Bi in 1Ag & 0.3Ag base SAC
- Improve properties by adding trace elements



Sn-Bi low-temp Paste

- Impact on shock strength
- Creep fatigue & max operating temp



- Sn-58Bi & Sn-57Bi-1Ag life time cannot be estimated
- No improvement on high-strain impact strength. High potential, but suspended for general use



Specialized Paste

- Effectiveness of additives
- Side effects



- Research market demand
- Unable to narrow down. May need to be customized by application. No progress

2. Quantification of properties using user-friendly methods



Challenge towards new test methods

3. Licensing terms for alloy candidates are RAND basis



Agreed upon at the start of project

2nd Gen. Solder Alloys Recommended by JEITA PG

Sn- 1Ag- 0.7Cu- 2Bi*

Sn-1Ag-0.7Cu-1.6Bi-0.2In

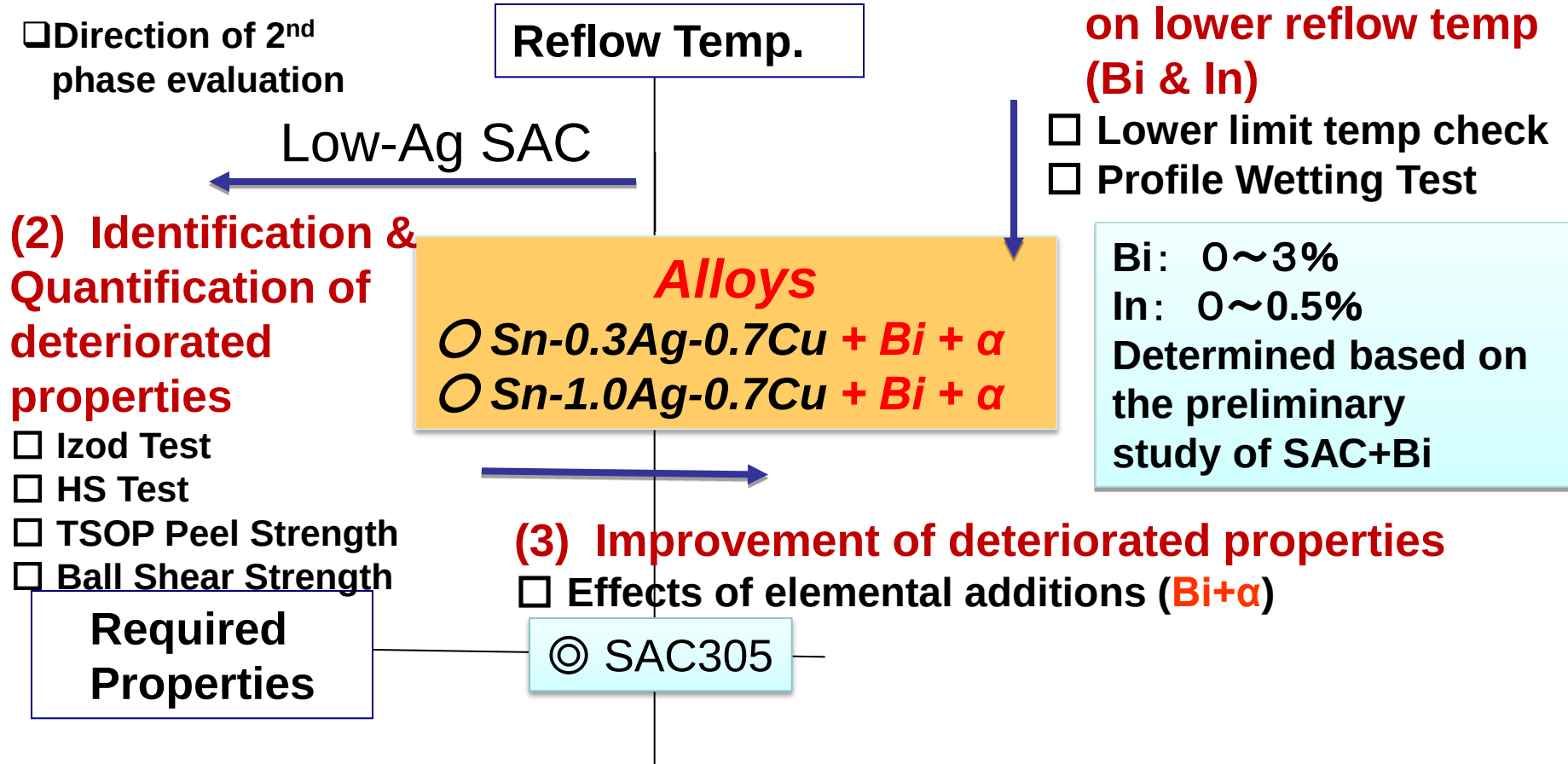
Why?

1. Compatible with SAC305 reflow profile
2. Similar mechanical properties and impact strength as SAC305

However, although not critical, below characters were observed:

1. High-strain thermal fatigue properties are slightly lower than SAC305
2. Stress can not be applied during cooling due to a gap between solidus & liquidus temperature

Evaluation: Alloys & Test Parameters



Tested Parameters and Alloys (Details)

Evaluation Parameters

- **Melting Point & Reflow Temperature**
 - **Reflow Profile & Requirement**
 - **Melting Test (Reflow Test)**
 - **Wetting Test**
- **Mechanical Strength Test**
 - **Chip shear test**
 - **High-speed shear test (Izod)**
 - **Impact bending test**
 - **Limit bending test**
 - **Thermal shock and fatigue test**

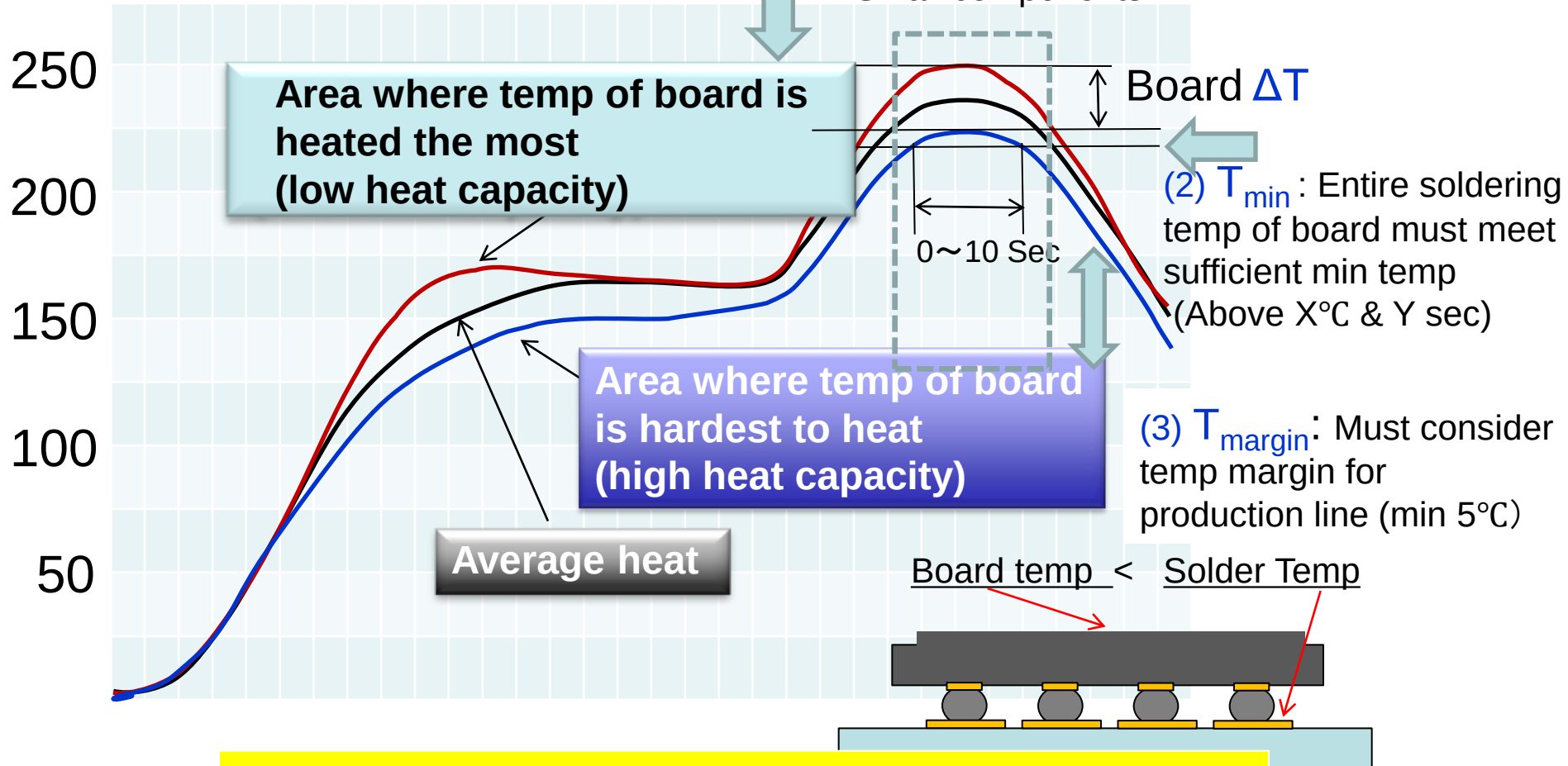
Evaluation Solder Candidates

No.	Sn	Ag	Cu	Bi	In	Other	Remarks
1	Bal	3	0.5				Ref: SAC305
2	Bal	1	0.7	1.6	0.2		Senju alloy code: M40
3	Bal	1	0.7				Evaluate the effects of Bi-doped SAC107
4	Bal	1	0.7	2			
5	Bal	1	0.7	3			
6	Bal	1	0.7	1			Evaluate the effects of In-doped SAC107+1Bi
7	Bal	1	0.7	1	0.2		
8	Bal	0.3	0.7	3			Evaluate the effects of In-doped SAC0307+3Bi
9	Bal	0.3	0.7	3	0.2		
10	Bal	1	0.5	3		Ni 50ppm	Evaluate the effects of Ni-doped SAC107+3Bi
11	Bal	1	0.7	1.5	0.2	+α	Harima Chemicals codes: LS1.0A1, LS1.0A2
12	Bal	1	0.7	1.5	0.5	0.5Sb +β	Evaluate the effects of Sb addition and In increase

Melting Point & Reflow Temperature

Reflow Profile

(1) T_p : Set the peak temp so that all components on the board must not exceed the allowable max temp.
Small components

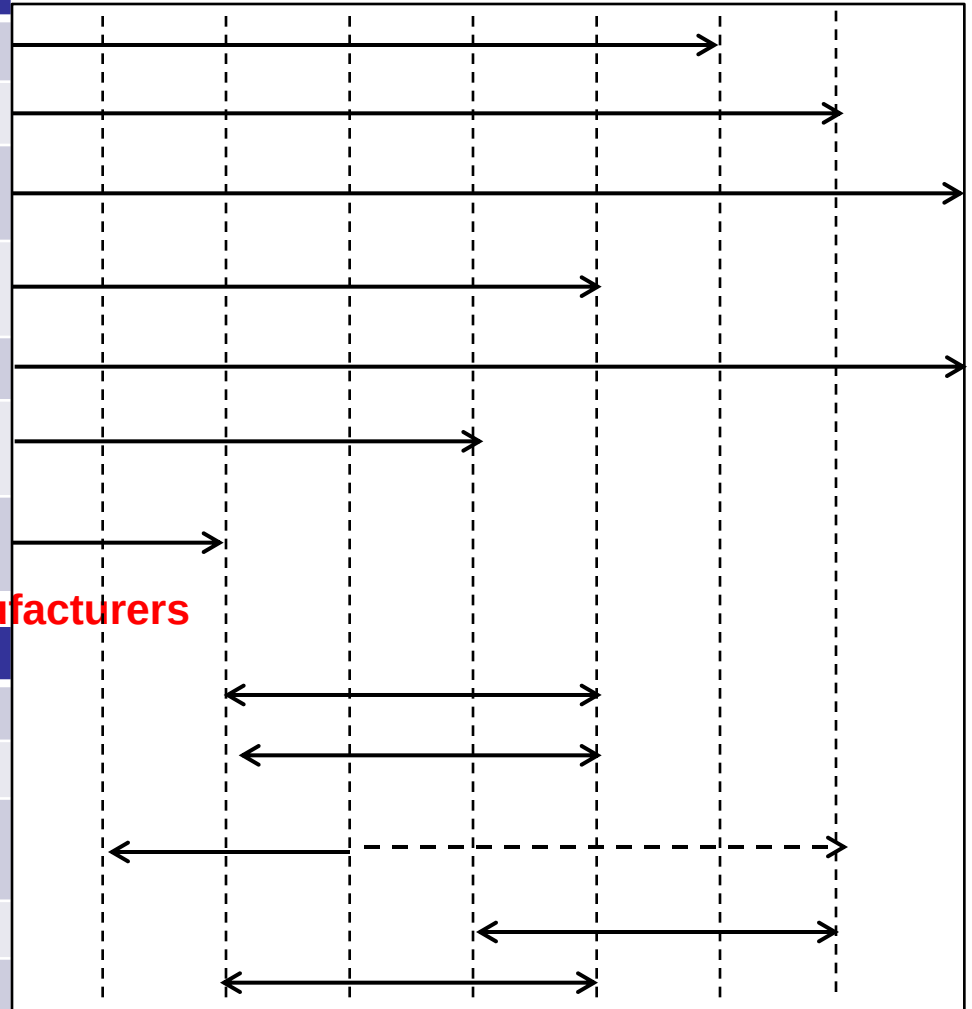


(Ex.) T_{min} : $T_p 260^{\circ}\text{C} - \Delta T 20^{\circ}\text{C} - T_{margin} 5^{\circ}\text{C} = 235^{\circ}\text{C}$
 $T_p 245^{\circ}\text{C} - \Delta T 15^{\circ}\text{C} - T_{margin} 5^{\circ}\text{C} = 225^{\circ}\text{C}$

Reflow Temp Requirements

Reflow heat resistance of components

Parts/Standards	Temp x Time, T_{max}	Max, T_{max}
IEC C60068-2-58	220°C X 60~90s	250°C
IEC C60068-2-58	220°C X ≤ 60 s	255°C
IPC/JEDEC J-STD 020D small & thin	217°C X 60~150s	260°C
IPC/JEDEC J-STD 020D large & thick	217°C X 60~150s	245°C
Semiconductor company "T"	230°C X 30~50s	260°C
Al electrolytic capacitor (medium)	220°C X ≤ 30 s	240°C
Al electrolytic capacitor (large)	217°C X ≤ 20 s	230°C



Solder reflow temp used by assembly manufacturers

Mfr	Min, T_{min}	Max, T_{max}	Diff, ΔT
S	230°C	245°C	15°C
P	232°C	245°C	13°C
T	Solder liquidus + (5~10°C)	Component heat resistance - (5~10°C)	-
A	240°C	255°C	15°C
F	230°C	245°C	15°C

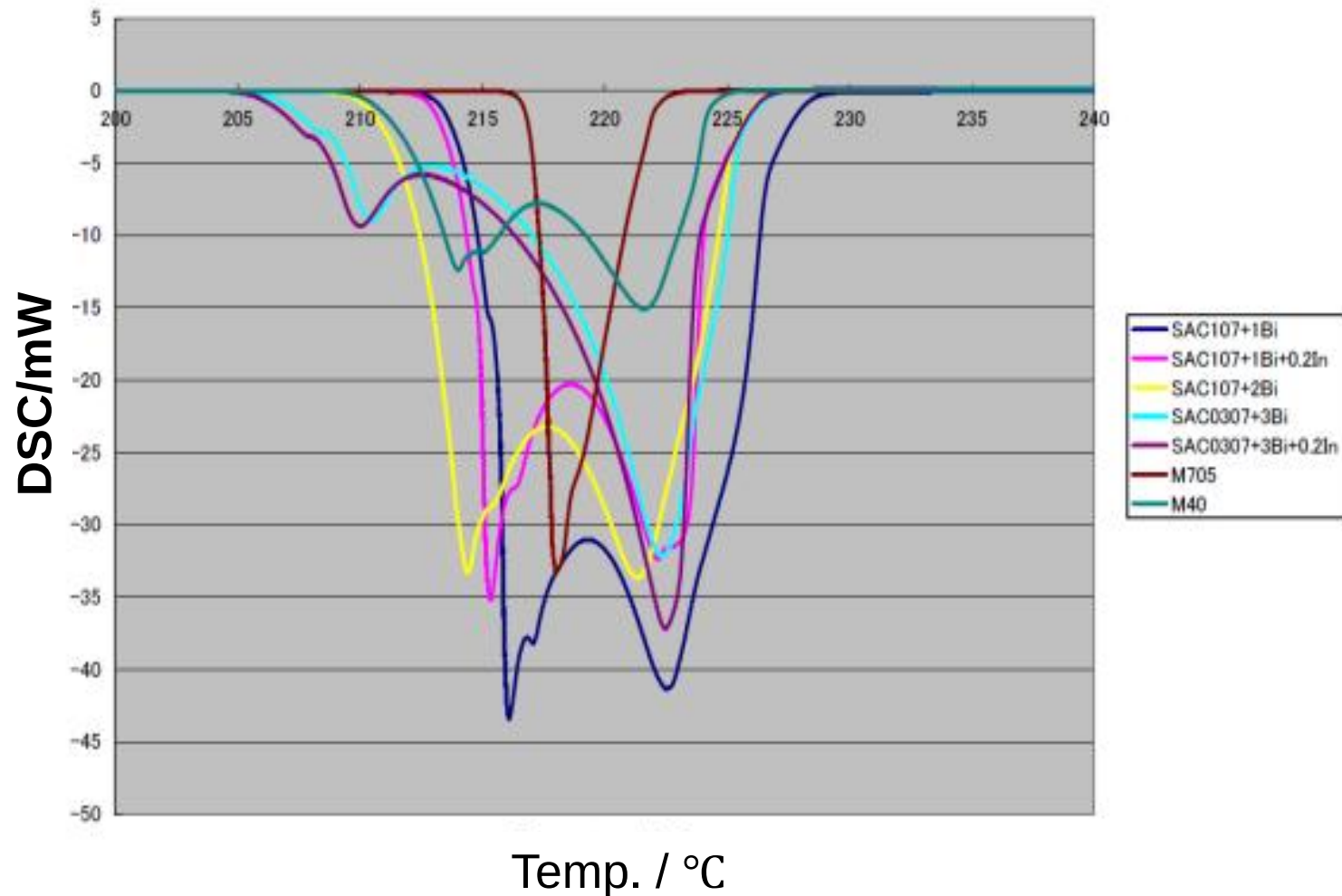
225 230 235 240 245 250 255 260
Max Temp, T_{max} (°C)

Summary of Temp. Requirements

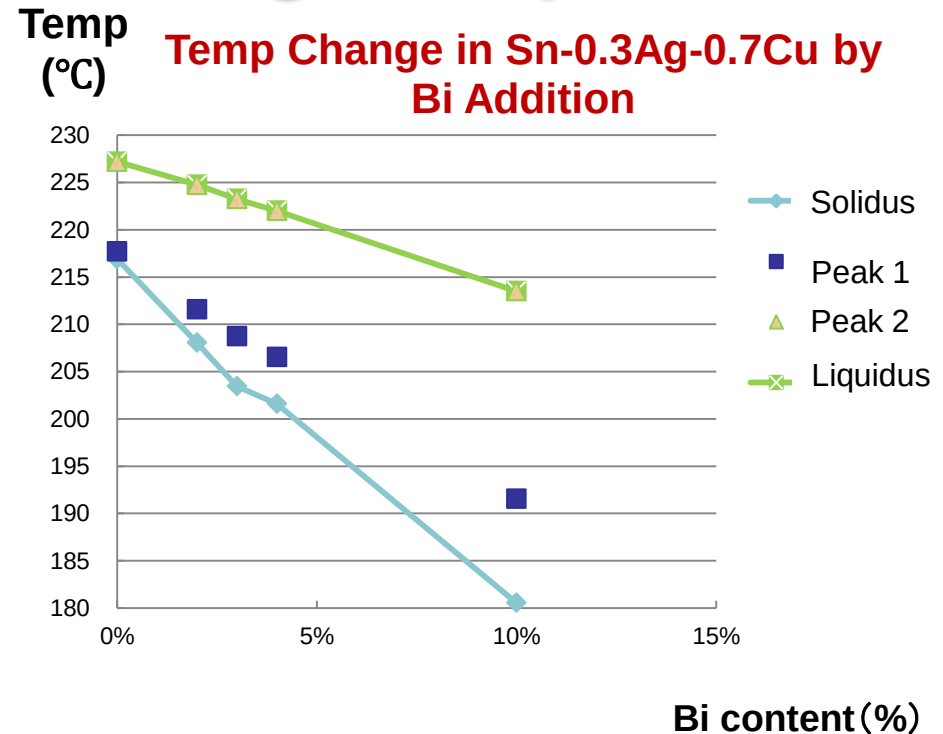
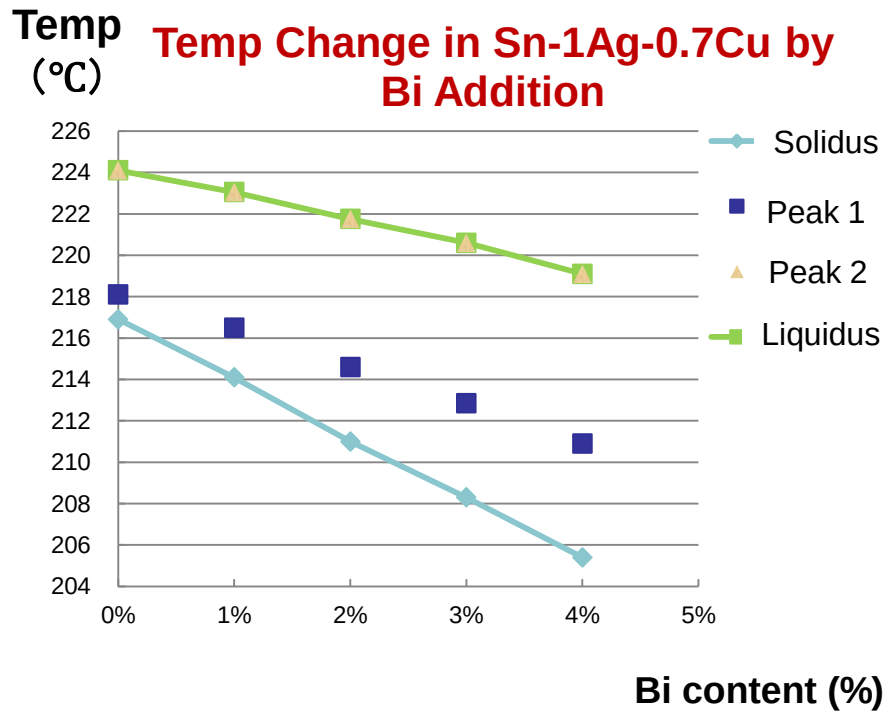
1. Reflow Limits should be defined as follows:
Highest set temp.= Heatproof temp. of parts — Temp. variation
Lowest set temp.= Liq. line temp. of solder + Temp. variation
2. Highest allowable surface temp. of parts is:
 - 260°C for typical semiconductors
 - 230°C for some large capacitors
 - and so on
3. It was concluded that the control of the reflow temp. profile was important and critical

Melting & Wetting Test

Melting Temperature Measurements (Ex; Results of DSC)



The Effect of Bi on Melting Temperature



- When 1% Bi is added to 1Ag alloy, solidus and liquidus temp will drop 3°C and 1°C respectively.
- When 1% Bi is added to 0.3Ag alloy, solidus and liquidus will drop 3.6°C and 1.3°C respectively.

Lower Limit Temperature in Reflow(1)

【Conditions】

Equipment : Reflow simulator
(Sanyo Seiko SP-5000DS)

Component : 8mm dia.
coil

Board size : 30mm x
30mm

Component location :
Center

Soldering Method :
Screen
print

【Method】

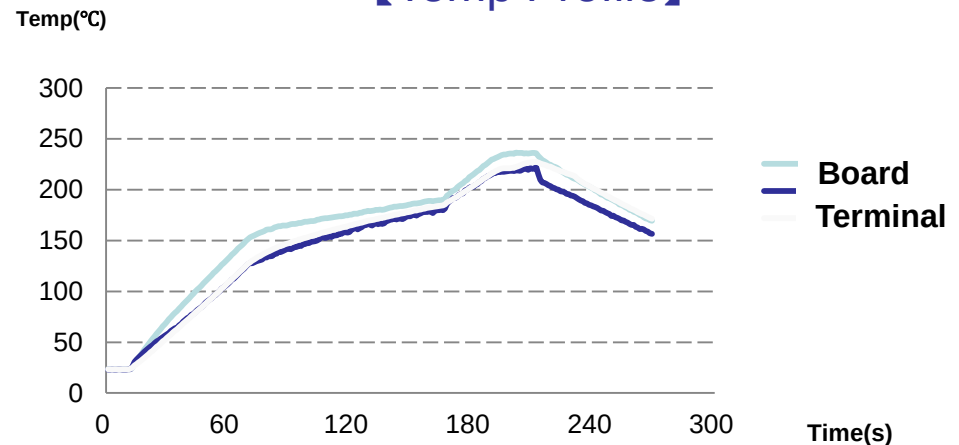
After heating with reflow
simulator, verify fillet
formation on the 8mm coil



○ : Fillet formed

× : Fillet not
formed

【Temp Profile】



Example: 225°C or higher for 10s

Lower Limit Temperature in Reflow

 Actual measurement (others are estimate)

Solder Composition					Sol- dus (°C)	Liq- dus (°C)	ΔT (°C)	Reflow Temp.(°C) (Hold for 10 sec.)										
Sn	Ag	Cu	Bi	In				220	221	222	223	224	225	226	227	228	229	230
Bal	3	0.5			217	218	1	✗			○	○	○	○	○	○	○	○
Bal	1	0.7	1.6	0.2	210	222	12	✗	✗	✗	✗		○	○	○	○	○	○
Bal	1	0.7			217	224	7	✗	✗	✗	✗	✗	✗	✗	✗			○
Bal	1	0.7	1		214	223	9	✗	✗	✗	✗	✗	✗		○	○	○	○
Bal	1	0.7	1	0.2	213	223	10	✗	✗	✗	✗	✗	✗		○	○	○	○
Bal	1	0.7	2		211	222	11	✗	✗	✗	✗		○	○	○	○	○	○
Bal	1	0.7	2		208	221	13	✗	✗	✗	✗		○	○	○	○	○	○
Bal	0.3	0.7	2		203	223	20	✗	✗	✗	✗	✗	✗		○	○	○	○
Bal	0.3	0.7	2	0.2	206	223	17	✗	✗	✗	✗	✗	✗		○	○	○	○

Summary of Lower Limit Temperature (Optical observation)

Against lower limit (230°C) reflow profile:

SAC305 : more than 5°C margin

107+2~3Bi : 5°C margin ensured

(M40) : 5°C margin ensured

SAC107+1Bi : Margin decreased to 3°C

SAC107 : No margin

Quantitative Approach

Wetting Test Method

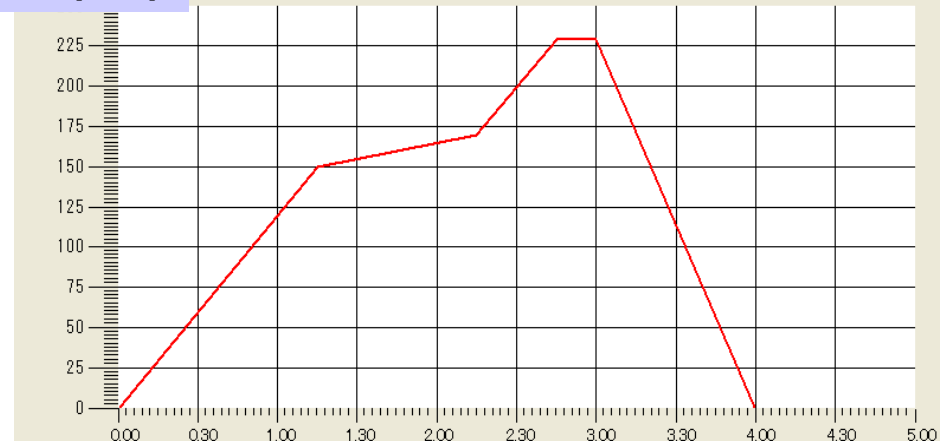
Displacement wetting test by profile heating

- Possible to compare wetting values using Cu coupon
- Possible to measure the temp & time at the start and the completion of wetting



Apparatus

Temp (°C)

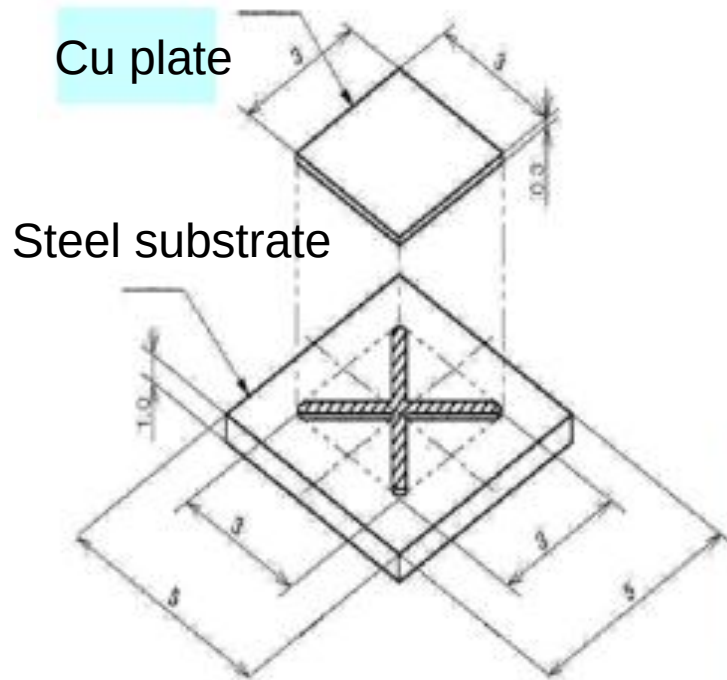


STEP	1	2	3	4	5	6
Time(min)	0.00	1.15	1.00	0.30	0.15	1.00
Temp.(°C)	0	150	170	230	230	0
Temp./Grad.(°C/s)	0	2	0.3	2	0	-3.8

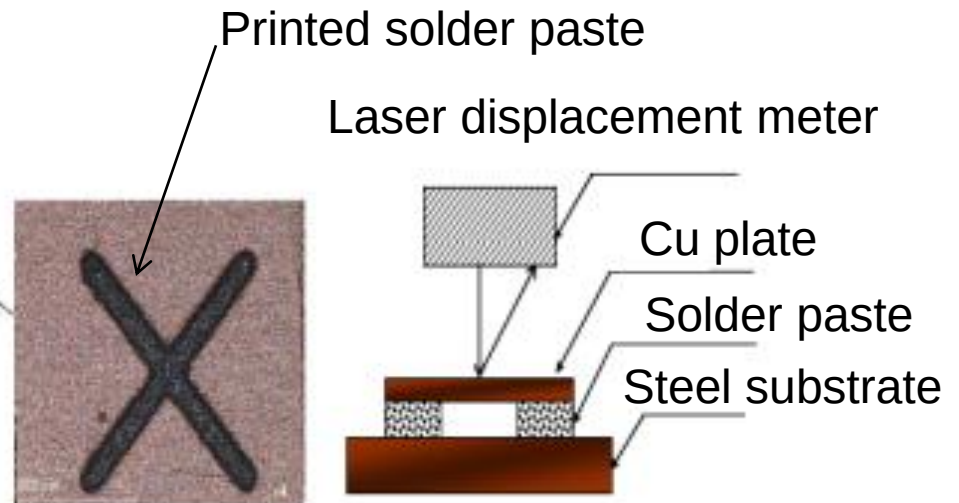
Temperature profile of wetting test

Test Piece

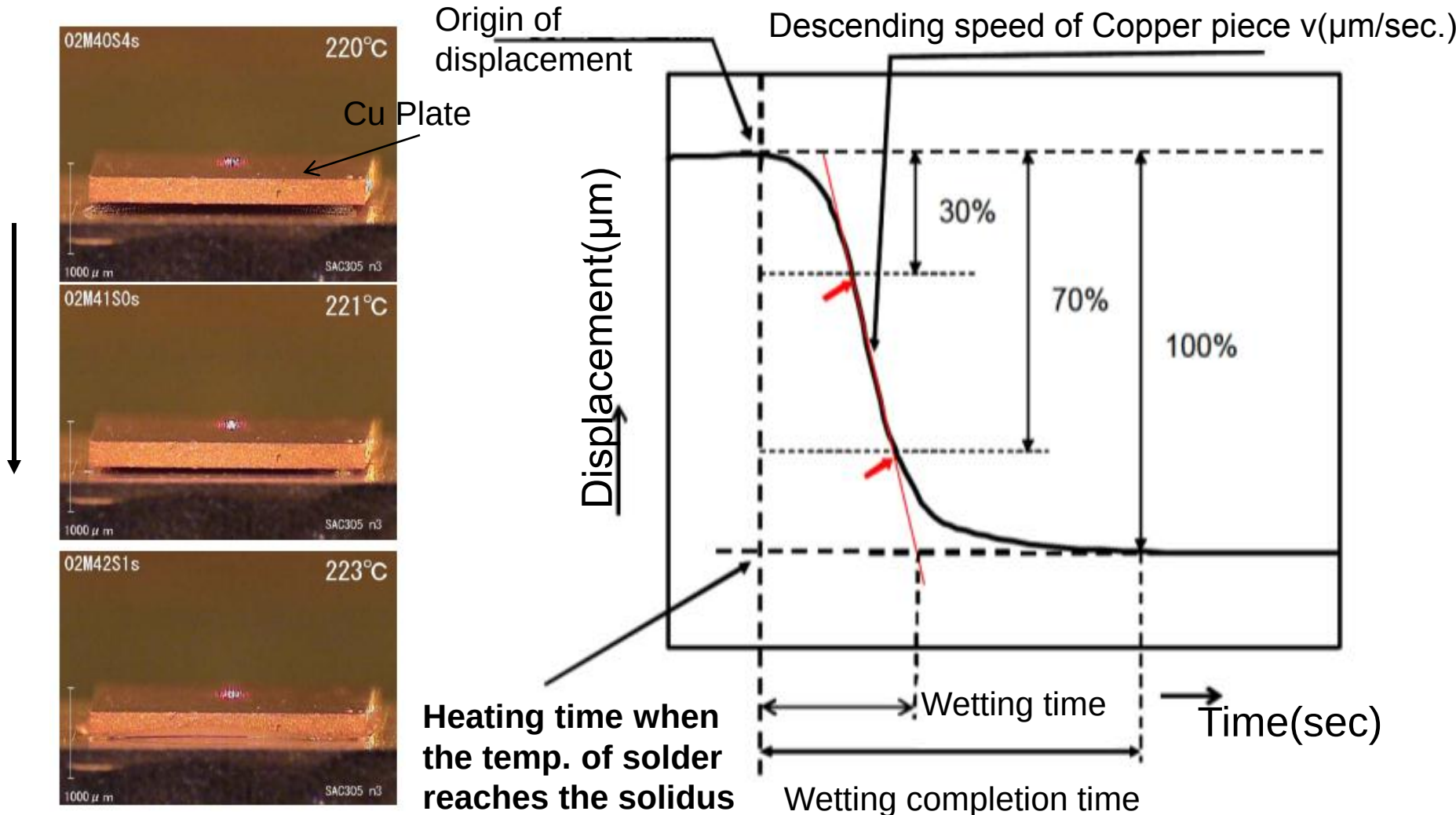
Steel substrate: 5 mm-square, $t=1.0$ mm
Copper piece: 3 mm-square, $t=0.3$ mm
(Weight: 24 mg)
Solder paste print thickness: 120 ± 10 μm
Mount height of copper piece: 90 ± 10 μm



Degreasing → Acid washing
→ Drying

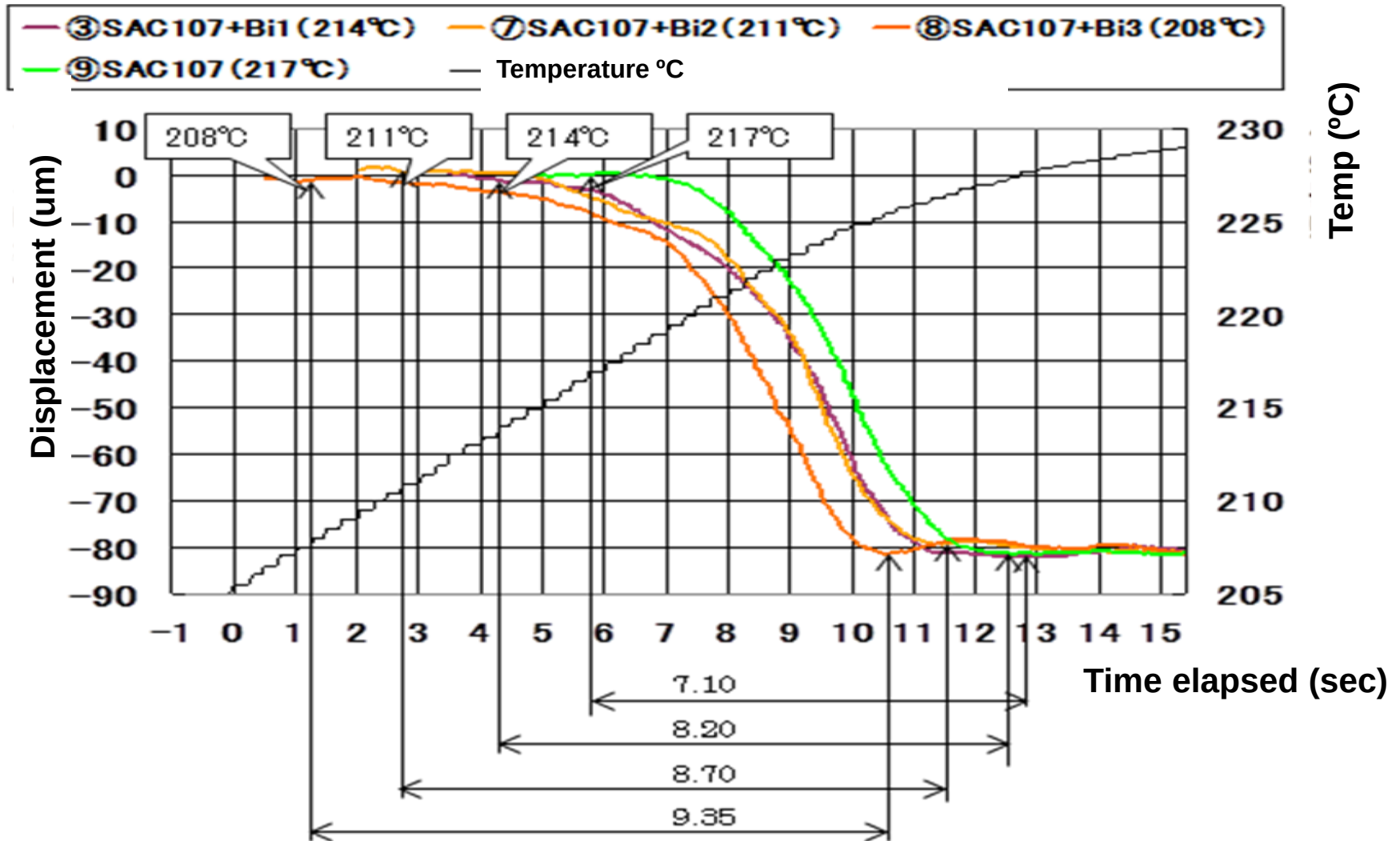


Evaluation Method



Schematic diagram of result(Displacement/Time relationship)

Ex. of Test Results



Summary of Wetting Test Results

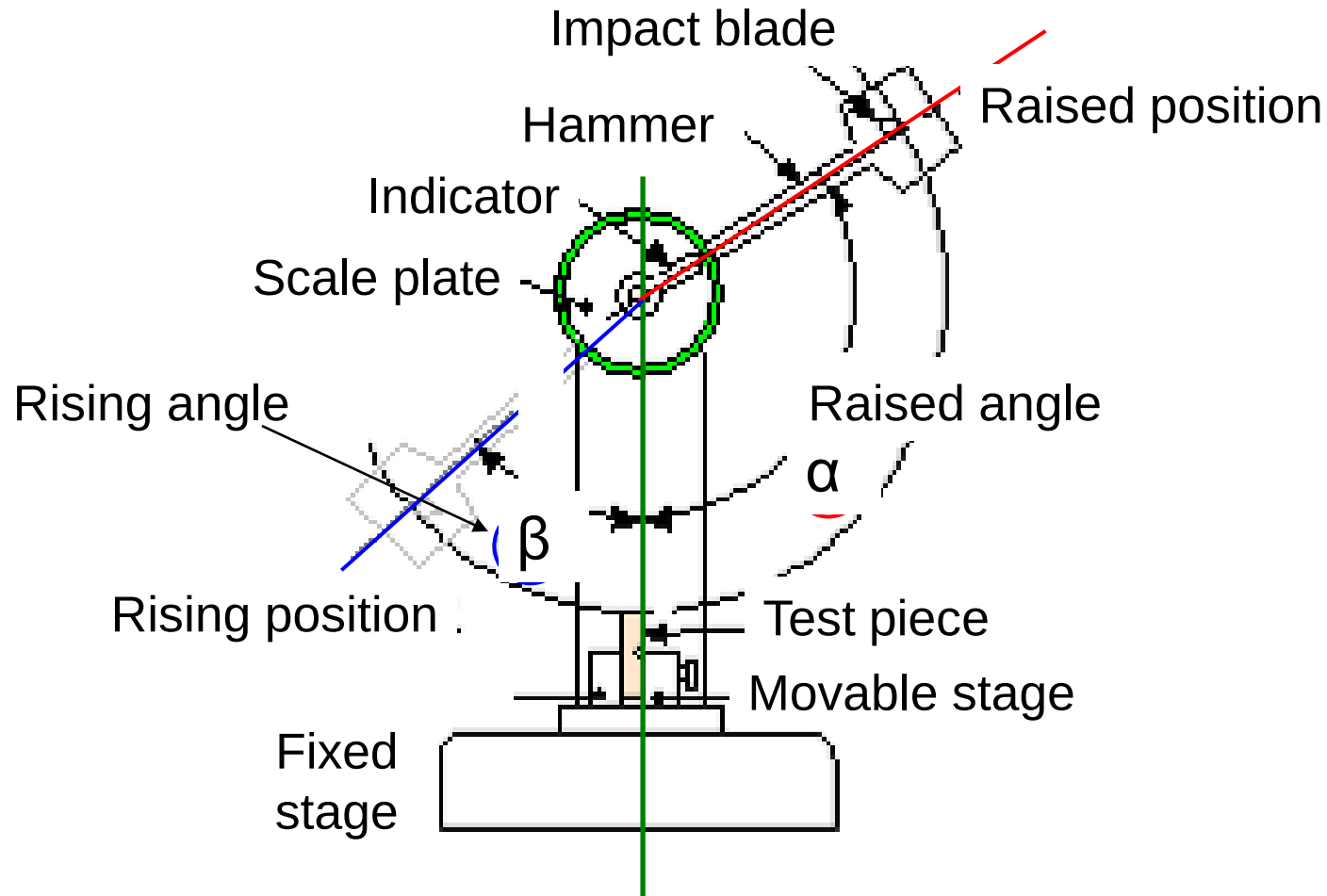
- By Bi addition, wetting start time & temp. become shorter and lower.
- Wetting finishing time & temp. also become shorter and lower.

As the results, the wetting property (solderability) was improved by Bi additions.

By Bi addition, we can achieve almost the same soldering temp. profiles as the SAC305 though using low Ag content(1%Ag) SAC solder.

Mechanical Strength Test

Izod Impact Test

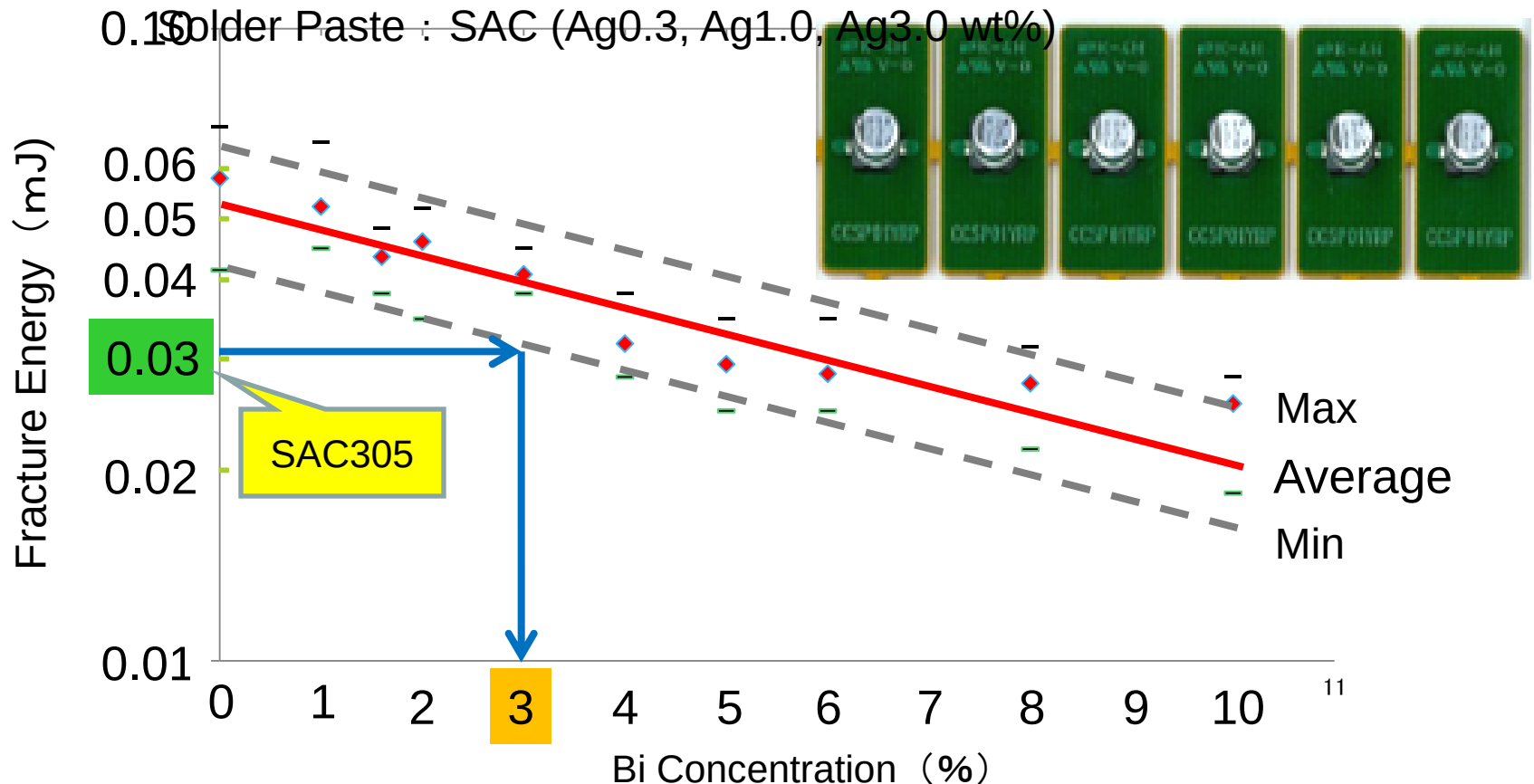


Fracture energy is obtained by the Izod Impact Test

The Effect of Bi Addition using Izod Impact Test

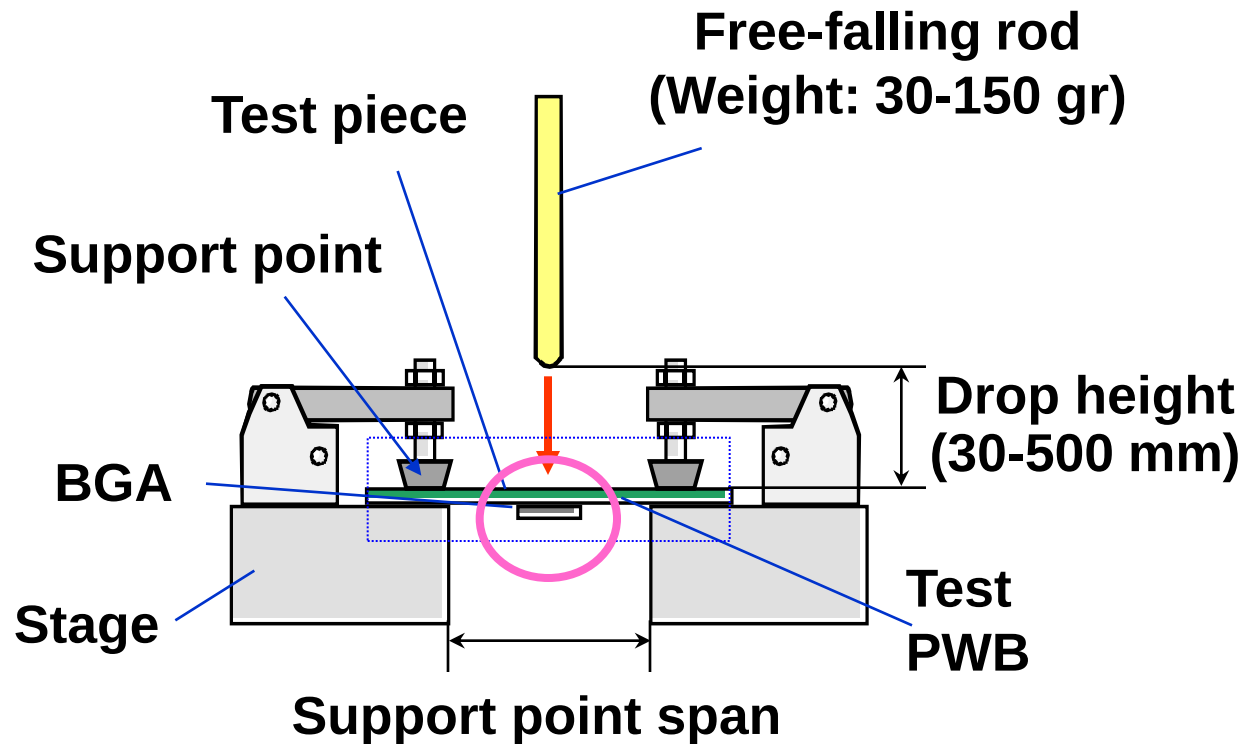
Component : Dia. 5mm Cap Aluminum (Nichicon UWT1C220MCR1GB)

Solder Paste : SAC (Ag0.3, Ag1.0, Ag3.0 wt%)



To meet SAC305 level, Bi content in SACB107 α must be **3wt% Max**

Substrate Bending Test (IBT)



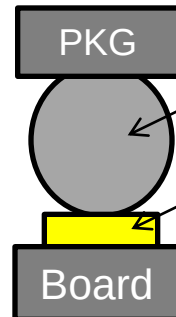
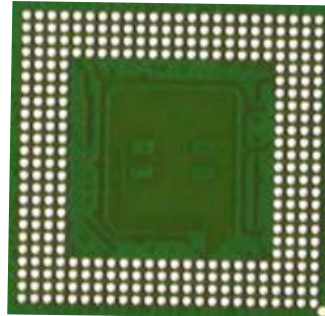
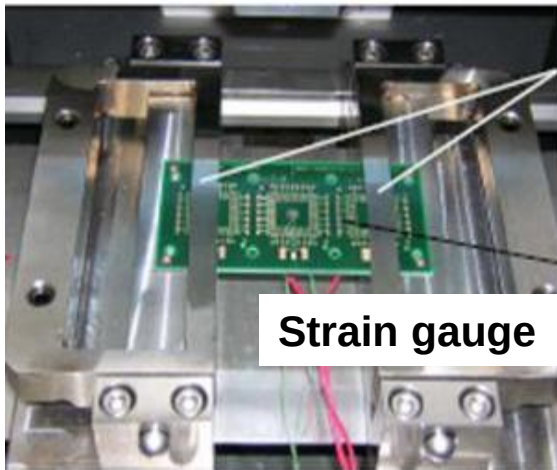
(ED-4702B)

Rod Drop Impact Test :
Impact Bending Test (IBT)

Evaluation can be done by measurement of strain and rod dropped numbers

Principle and apparatus

Substrate Bending Test (IBT)



BGA ball

Paste

<Board>

Material : FR4

Pad : Cu-OSP

Outline : 30x120x1.6mmt

<Sample>

BGA : 1313-224 pins(0.5mP)

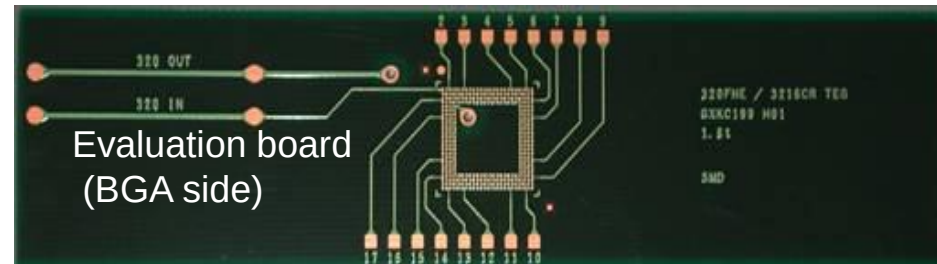
PKG pad : Electrolytic Ni/Au

Ball alloy: SAC305 &SAC105

Ball dia : 0.3mm

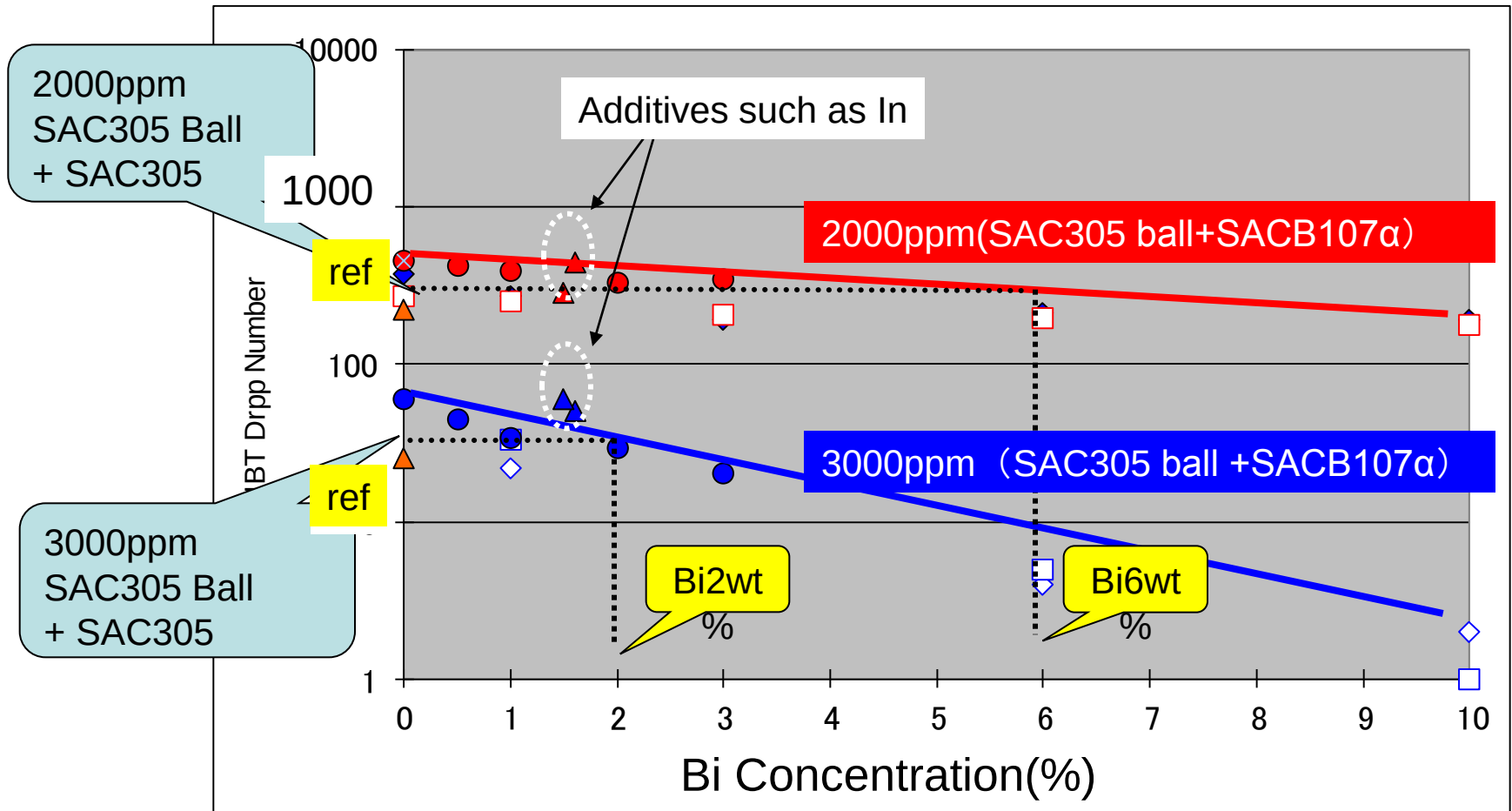
<Reflow Profile>

Peak 235°C



Test Piece and placement

IBT Evaluation Results

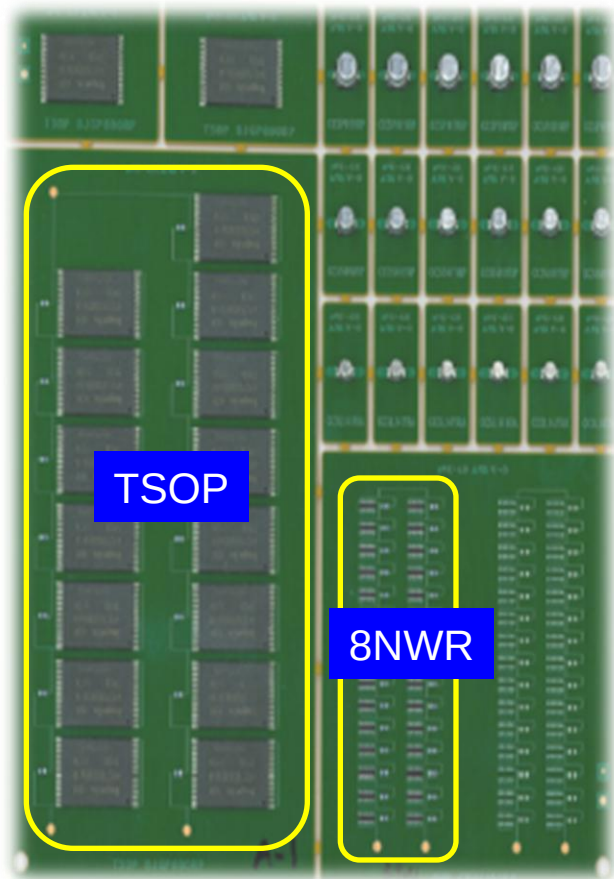


Summary of Izod & IBT Tests

- (1) The addition of Bi to SAC107 should be limited to 3 mass% Max. by the results of Izod impact tests.
- (2) For SAC305 ball & SACB107 paste combination, SAC305 equivalent level can be met when Bi is 6% for IBT (2000ppm) and 2% for IBT(3000ppm).
- (3) For high-impact IBT (3000ppm strain), additives such as In are found to be effective.

Thermal Fatigue Test

Sample of Thermal Fatigue Test

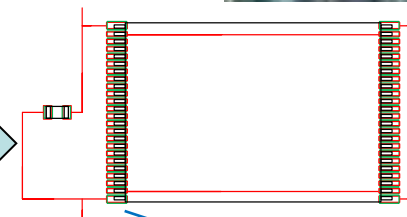


Components:

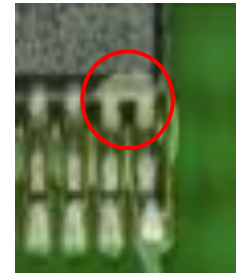
(1) Eight-ganged network resistor (8NWR)



(2) TSOP



Short caused by Ag paste

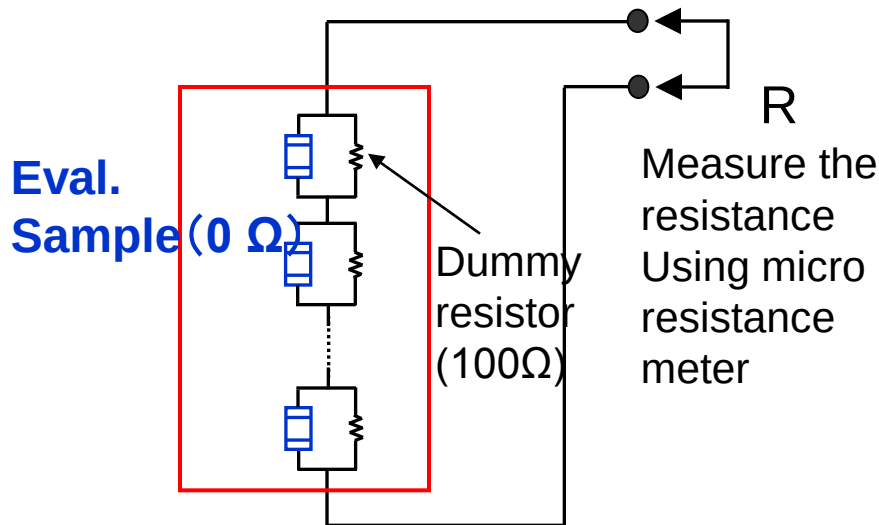


Board	: FR-4
Size	: 160 x16mm
Thickness	: 1.6mm
Screen thickness	: 120μm

Test board and specimen

Method of Thermal Fatigue Test

Procedure:



Connect evaluation sample & dummy resistor (**1608 size 100Ω**) in parallel, then connect **n=30** in series



If open is found in one sample, detect the 100Ω of dummy resistor



By using micro meter, detect the change in resistance and determine the cycle where cracks had occurred (electrical opens)



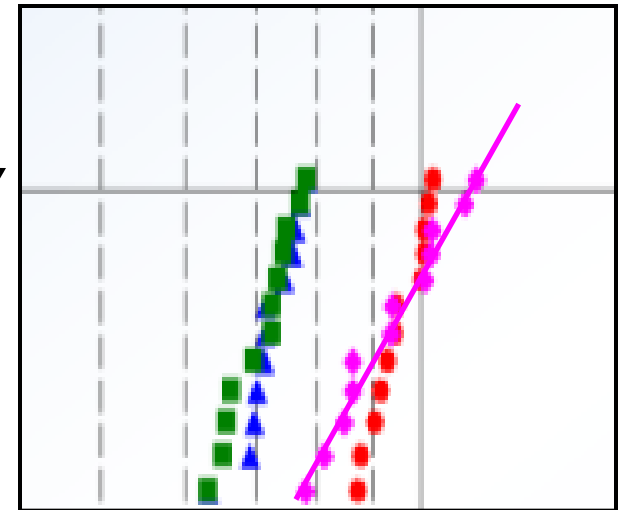
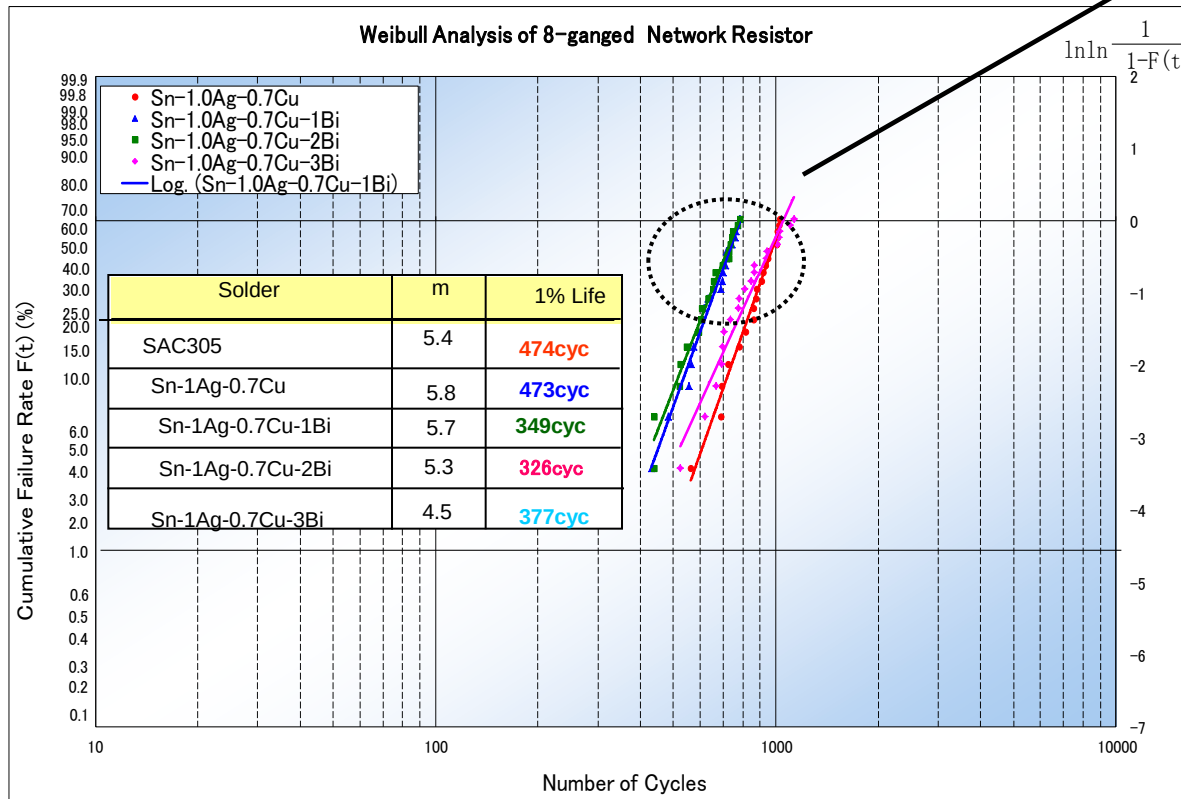
Perform **Weibull analysis** and compute the cycle numbers at 1% cumulative failure rate

Test Conditions:

— 25~125°C(20min./cyc.)
~1500 cycles

Thermal shock test chamber

Examples of Thermal Fatigue Test Results (8NWR)



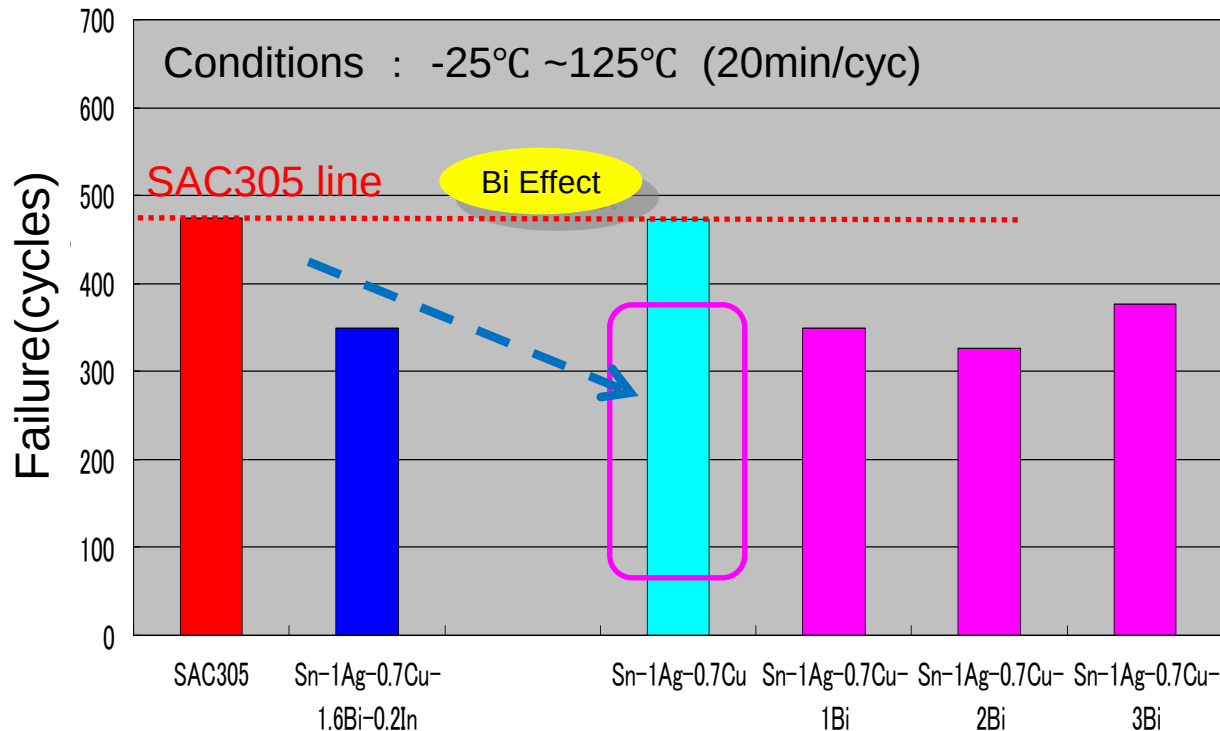
m values in the failure region

Solder	m
Sn-1Ag-0.7Cu	5.8
Sn-1Ag-0.7Cu-1Bi	6.5
Sn-1Ag-0.7Cu-2Bi	4.8
Sn-1Ag-0.7Cu-3Bi	2.8

8NWR; 8 Ganged Net Work Resister

Thermal Fatigue Test Results (8NWR)

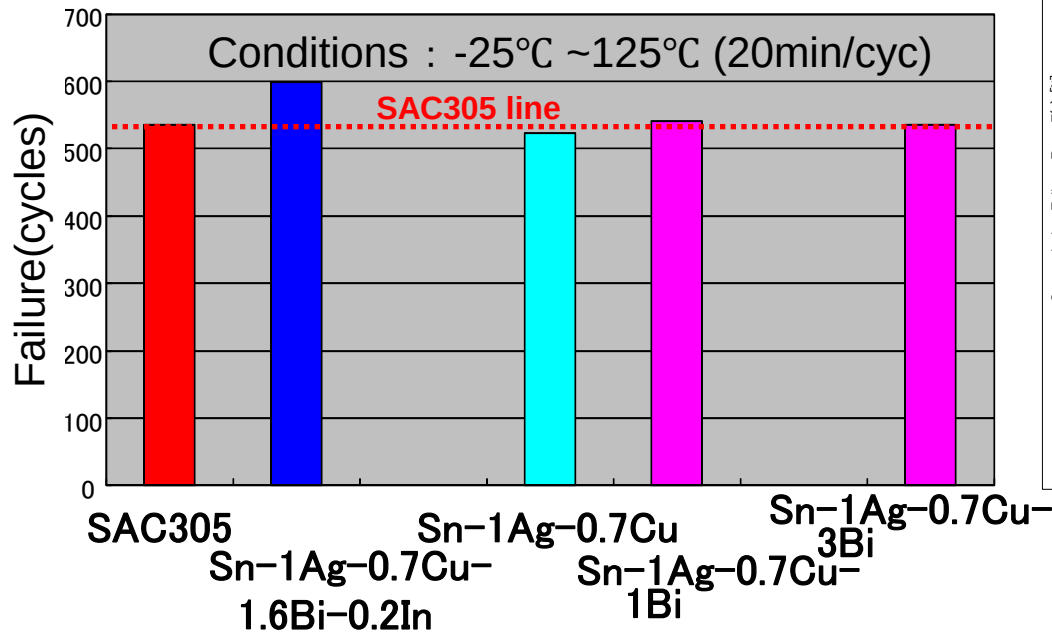
8NWR Thermal Fatigue Test Results (Effect of Bi)



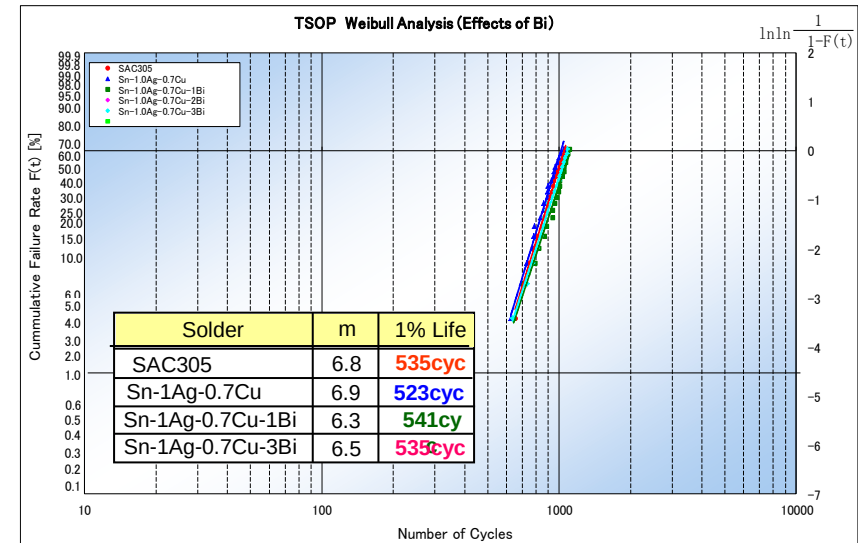
*Definition of “similar” : Nearly the same Weibull slope & cycle # at 1% cumulative failure rate is within $\pm 10\%$

- Thermal fatigue life of Sn-1Ag-0.7Cu is similar* to that of SAC305
- The life of Sn-1Ag-0.7Cu drops by 20~30% when 1~3% of Bi is added.
 - ※ As compared to Bi1% & Bi2%, the Weibull slope of Bi3% is different and therefore the failure mode is likely to be different

Thermal Fatigue Test Results (TSOP)



**TSOP Thermal Fatigue Test Results
(Effect of Bi)**



Previous test results Conditions: -40°C ~125°C (60min/cyc)

Base Solder	B content (%)	200cyc	400cyc	600cyc
Sn-1Ag-0.7Cu	0	0/3 NG	0/3 NG	2/3 NG
	3	0/5 NG	0/5 NG	1/5 NG
	5	0/5 NG	3/5 NG	5/5 NG
	8	0/5 NG	4/5 NG	5/5 NG
	10	0/5 NG	5/5 NG	5/5 NG

Dramatic drop in life when Bi is added by 5% or more

Summary of Thermal Fatigue Test

- (1) Thermal fatigue life of Sn-1Ag-0.7Cu is similar to that of SAC305
- (2) Life of Sn-1Ag-0.7Cu similar when 1% & 3% Bi are added ⇒ Same results as previous small quantity testing
- (3) Slight increase in life for Sn-1Ag-0.7Cu-1.6Bi-0.2In as compared to SAC305 (by 10%)

Summary & Conclusion

■ Selection of **low-Ag SAC** alloy

Based on the evaluation results,

Sn-1Ag-0.7Cu-2Bi and **Sn-1Ag-0.7Cu-1.6Bi-0.2In** are the recommended alloys for the low-Ag alternatives.

Both Sn-0.3Ag-0.7Cu & Sn-1.0Ag-0.7Cu are potential candidates for the alternative alloys. However, the lowest allowable heating temp. is the major weakness of these alloys. According to the test results, when the peak temp is set at 230°C the following can be summarized against the melting temp limit.

1. **The current SAC305 has a margin of 5°C+ α**
2. **SAC107 has no margin at the lower limit**
3. **SAC107 + 2%Bi ensures a margin of 5°C**

■ Low-temp and specialized alloys

This project has been suspended because industry-wide standard alloy cannot be identified. We look forward to the developmental activities by others.

Project Activities

Leader : Koji Serizawa
Sub-leader : Kenichi Tomitsuka

Committee Members:

Alps Electric, Casio Computer, Cookson Electronics, KOA, Sanyo Seiko, Senju Metal Industry, Sony, Tamura Corp, Techno Office Yamamoto, Toshiba, Nihon Genma, NEC, Nihon Handa, Nippon Filler Metals, Harima Chemicals, Panasonic, Hitachi, Fujitsu Laboratories, Fujitsu Advanced Technologies, Henkel Japan, Murata Manufacturing Co, Renesas Electronics

1 st PG Prep Meeting	May 2010		Discussion of project direction
2 nd PG Prep Meeting	June 2010		
1 st Meeting	Aug. 2010		Phase 1 alloy composition proposal
2 nd Meeting	Sep. 2010		
3 rd Meeting	Nov. 2010		Evaluation test methods planning
4 th Meeting	Jan. 2011		
5 th Meeting	Mar. 2011		Phase 1 evaluation result summary
6 th Meeting	May 2011		Phase 2 alloy composition proposal & eval planning
7 th Meeting	July 2011		
8 th Meeting	Sep. 2011		Phase 1.5 evaluation & release of interim report
9 th Meeting	Nov. 2011		
10 th Meeting	Jan. 2012		
11 th Meeting	Apr. 2012		Phase 2 evaluation result summary
12 th Meeting	May 2012		
13 th Meeting	Aug. 2012		Summarize recommended compositions & write-up report
14 th Meeting	Oct. 2012		

Review of Interim Report (Phase 1 Evaluation)

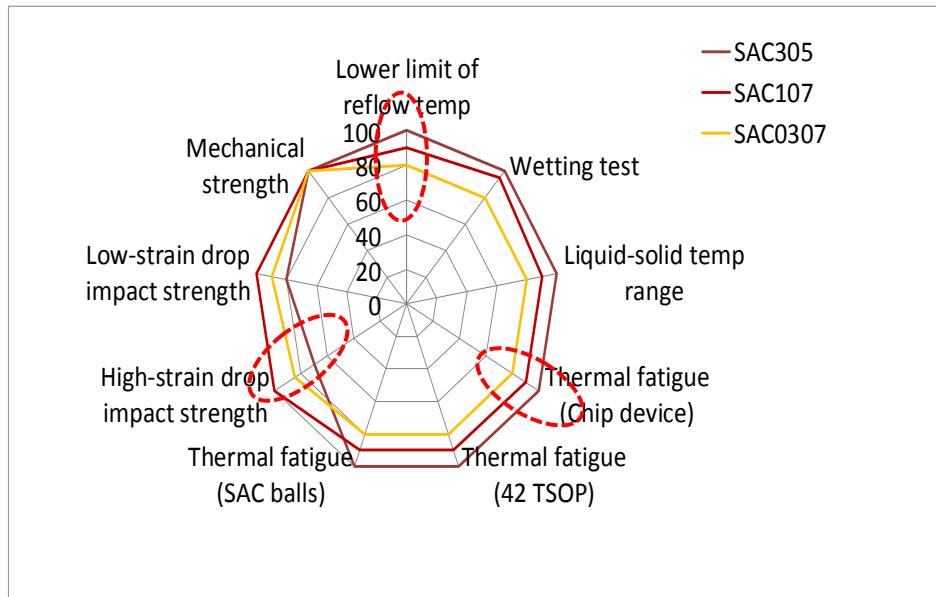
- **Sn-1.0Ag-0.7Cu**

Recommended as alternative alloy to SAC305

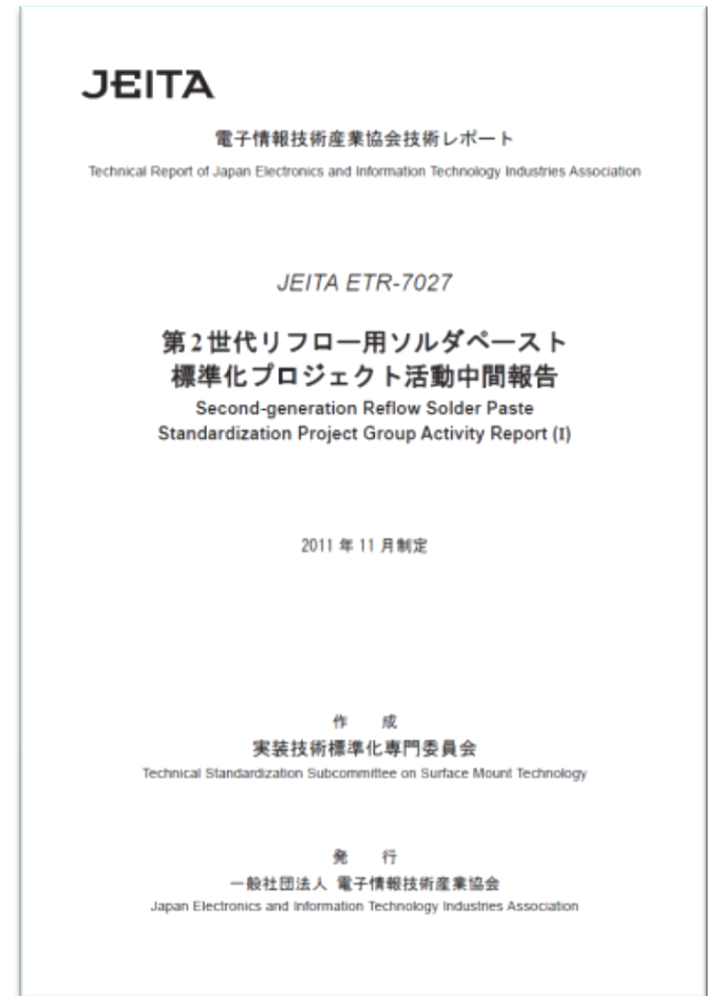
In addition,

- **Sn-0.3Ag-0.7Cu**

Recommended under limited conditions due to constraint in peak reflow temperature

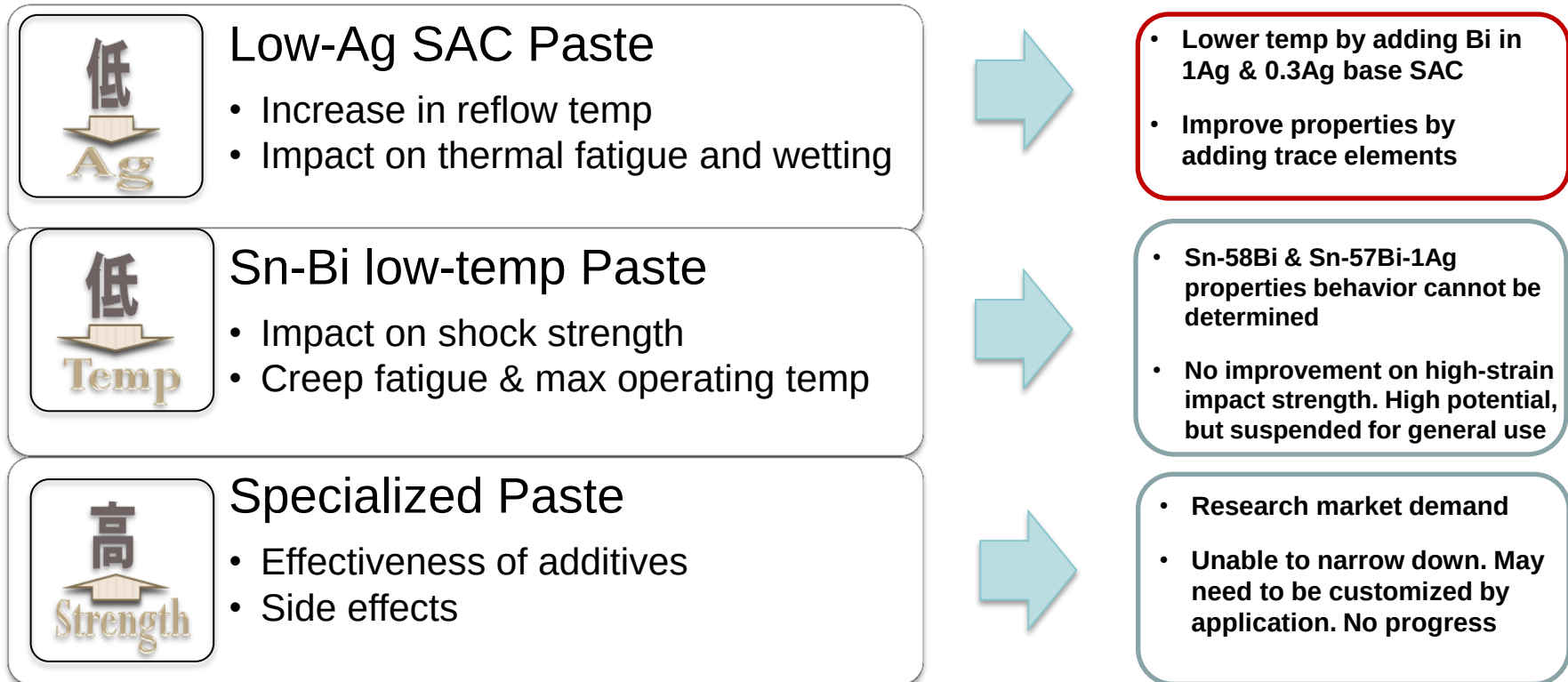


Difference in properties between SAC305 and low-Ag



Project Action Plans

1. Obtain suggestions from the solder manufactures



2. Quantification of properties using use-friendly methods  Challenge towards new test methods

3. Licensing terms for alloy candidates are RAND basis  Agreed upon at the start of project

2nd Gen Solder Alloy Recommended by JEITA PG

Sn- 1Ag- 0.7Cu- 2Bi*

Why?

1. Compatible with SAC305 reflow profile
2. Similar mechanical properties and impact strength as SAC305

However,

1. High-strain thermal fatigue properties are lower than SA305
2. Stress can not be applied during cooling due to a gap between solidus & liquidus temp

Phase 2 Evaluation: Alloys & Test Parameters

□ Direction of 2nd phase eval

Low-Ag SAC

Reflow Temp

(2) Identification & Quantification of deteriorated properties

- Izod Test
- HS Test
- TSOP Peel Strength
- Ball Shear

○ Sn-0.3Ag-0.7Cu + Bi + α
○ Sn-1.0Ag-0.7Cu + Bi + α

(3) Improvement of deteriorated properties

- Effects of elemental dopants

(1) Verification of effect on lower reflow temp (Bi & In)

- Lower limit temp check
- Profile Wetting Test

Bi: 0~3%

In: 0~0.5%

Determined based on the preliminary study of SAC+Bi

Required Properties

© SAC305

SAC & SnBi	SAC0.3 & SAC1.0	SN58B1 & 57Bi1Ag	Standard & Heat limit
○	×	×	×
○	○	—	×
○	○	×	×
○	×	×	×
○	○	○	×
○	○	×	—
○	○	○	—

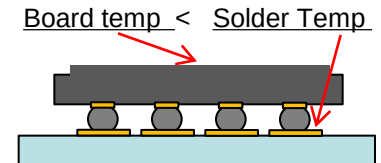
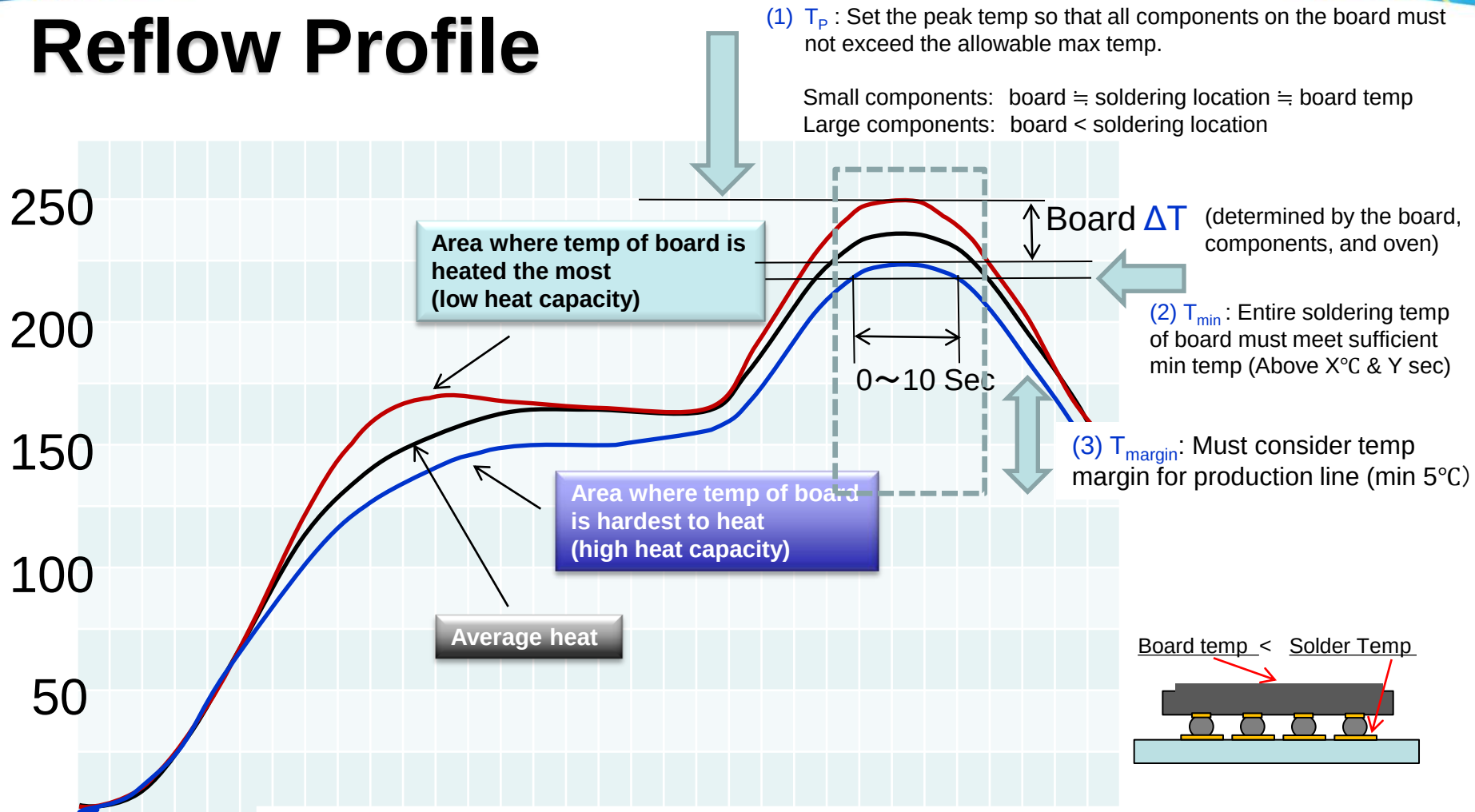
- Chip shear test
- High-speed shear test
- Impact bending test
- Limit bending test
- Thermal shock and fatigue test
- Meniscograph test
- Spreading test

Phase 2 Evaluation Solder Candidates

N o.	Sn	Ag	Cu	Bi	In	Others	Remarks
1	Bal	3	0.5				Ref: SAC305
2	Bal	1	0.7	1.6	0.2		(Senju alloy code: M40)
3	Bal	1	0.7				Evaluate the effects of Bi-doped SAC107
4	Bal	1	0.7	2			
5	Bal	1	0.7	3			
6	Bal	1	0.7	1			Evaluate the effects of In-doped SAC107+1Bi
7	Bal	1	0.7	1	0.2		
8	Bal	0.3	0.7	3			Evaluate the effects of In-doped SAC0307+3Bi
9	Bal	0.3	0.7	3	0.2		
10	Bal	1	0.5	3		Ni 50ppm	Evaluate the effects of Ni-doped SAC107+3Bi
11	Bal	1	0.7	1.5	0.2	+α	(Harima Chemicals codes: LS1.0A1, LS1.0A2) Evaluate the effects of Sb addition and In increase
12	Bal	1	0.7	1.5	0.5	0.5Sb+β	

Melting Point & Reflow Temperature

Reflow Profile



(Ex.) T_{min} : $T_P 260^{\circ}\text{C} - \Delta T 20^{\circ}\text{C} - T_{margin} 5^{\circ}\text{C} = 235^{\circ}\text{C}$
 $T_P 245^{\circ}\text{C} - \Delta T 15^{\circ}\text{C} - T_{margin} 5^{\circ}\text{C} = 225^{\circ}\text{C}$

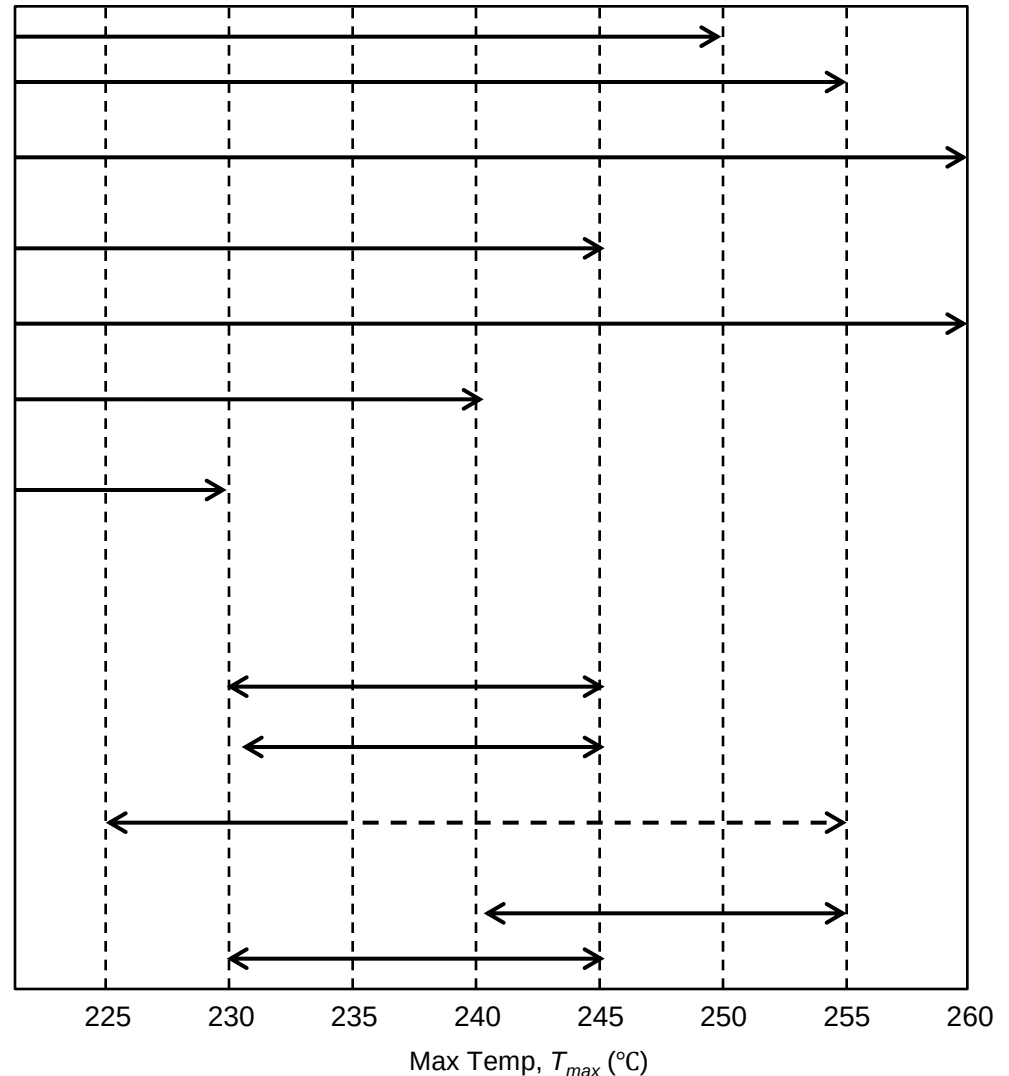
Reflow Temp Requirements

Reflow heat resistance of components

Parts/Standards	Temp x Time, T_{max}	Max, T_{max}
JIS C60068-2-58	220°C X 60~90s	250°C
JIS C60068-2-58	220°C X ≤ 60 s	255°C
IPC/JEDEC J-STD 020D small & thin	217°C X 60~150s	260°C
IPC/JEDEC J-STD 020D large & thick	217°C X 60~150s	245°C
Semiconductor company "T"	230°C X 30~50s	260°C
Al electrolytic capacitor (medium)	220°C X ≤ 30 s	240°C
Al electrolytic capacitor (large)	217°C X ≤ 20 s	230°C

Solder reflow temp used by assembly manufacturers

Mfr	Min, T_{min}	Max, T_{max}	Diff, ΔT
S	230°C	245°C	15°C
P	232°C	245°C	13°C
T	Solder liquidus +(5~10°C)	Component heat resistance -(5~10°C)	-
A	240°C	255°C	15°C
F	230°C	245°C	15°C

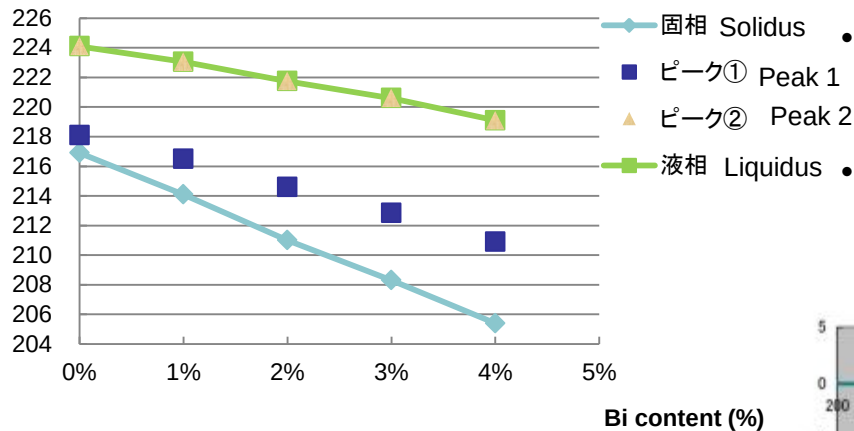


Melting & Wetting Test

The Effect of Bi on Melting Temp

Temp (°C)

Temp Change in Sn-1Ag-0.7Cu by Bi Addition

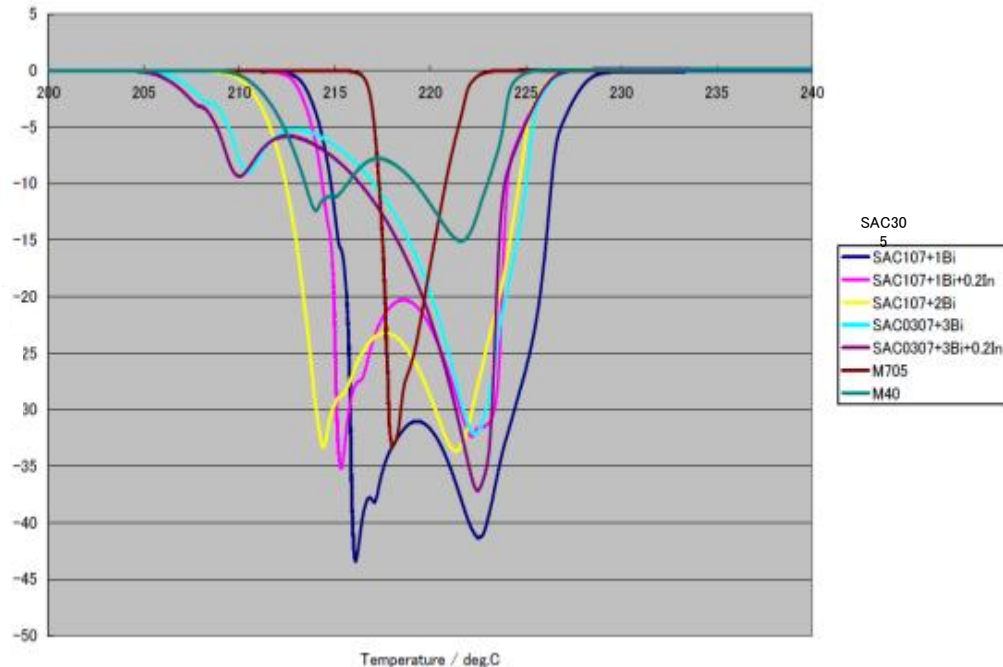
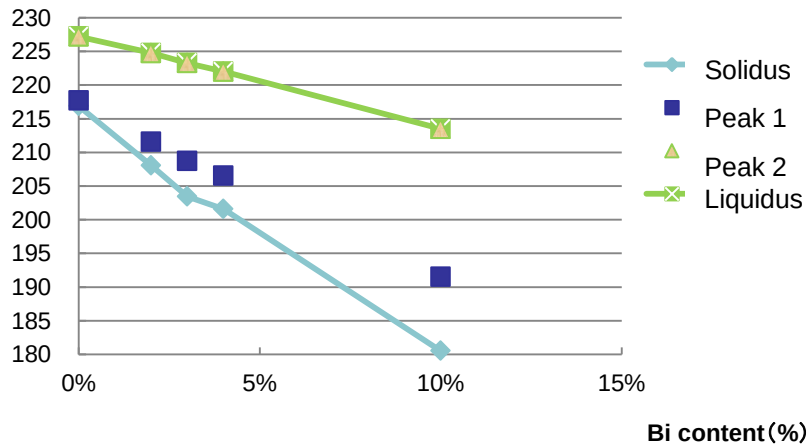


• When 1% Bi is added to 1Ag alloy, solidus and liquidus temp will drop 3°C and 1°C respectively.

• When 1% Bi is added to 0.3Ag alloy, solidus and liquidus will drop 3.6°C and 1.3°C respectively.

Temp (°C)

Temp Change in Sn-0.3Ag-0.7Cu by Bi Addition



Lower Limit Temp in Reflow

【Conditions】

Equipment : Reflow simulator (Sanyo Seiko SP-5000DS)

Component : 8mm dia. coil
Board size : 30mm x 30mm
Component location : Center
Soldering Method : Screen print

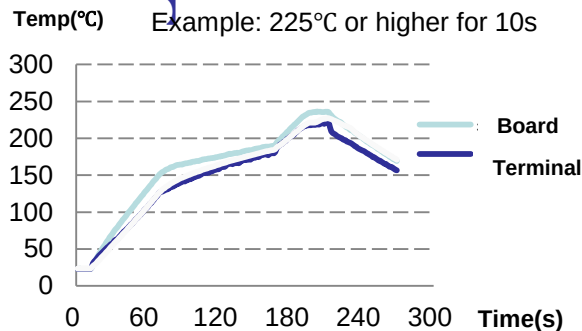


【Method】

After heating with reflow simulator, verify fillet formation on the 8mm coil

【Temp Profile】

Example: 225°C or higher for 10s



○ : Fillet formed



× : Fillet not formed

Against lower limit (230°C) reflow profile:

SAC305 : more than 5°C margin

107+2~3Bi : 5°C margin ensured

(M40) : 5°C margin ensured

SAC107+1Bi : Margin decreased to 3°C

SAC107 : No margin

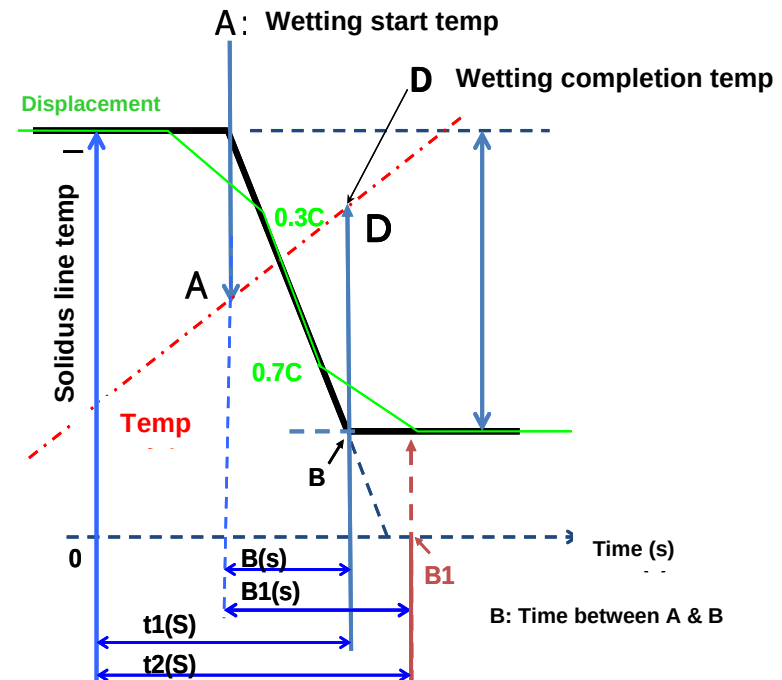
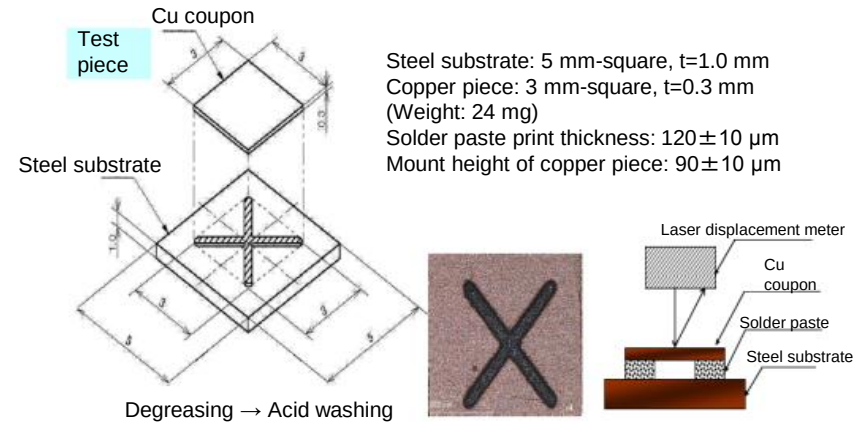
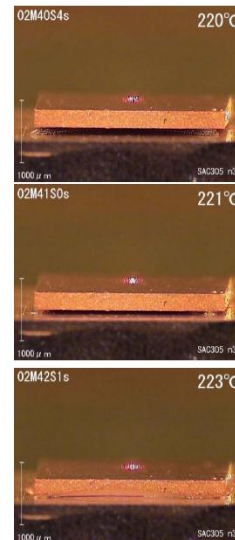
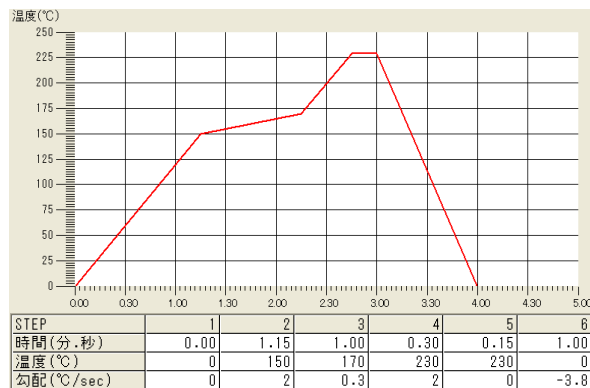
Actual measurement (others are estimate)

Solder Composition					Solidus s (°C)	Liquidus (°C)	Delta (°C)	Reflow Temp(°C) (Hold for 10 sec)									
Sn	Ag	Cu	Bi	In				220	221	222	223	224	225	226	227	228	229
Bal	3	0.5			217	218	1	×			○	○	○	○	○	○	○
Bal	1	0.7	1.6	0.2	210	222	12	×	×	×	×		○	○	○	○	○
Bal	1	0.7			217	224	7	×	×	×	×	×	×	×			○
Bal	1	0.7	1		214	223	9	×	×	×	×	×		○	○	○	○
Bal	1	0.7	1	0.2	213	223	10	×	×	×	×	×		○	○	○	○
Bal	1	0.7	2		211	222	11	×	×	×	×		○	○	○	○	○
Bal	1	0.7	3		208	221	13	×	×	×	×		○	○	○	○	○
Bal	0.3	0.7	3		203	223	20	×	×	×	×	×		○	○	○	○
Bal	0.3	0.7	3	0.2	206	223	17	×	×	×	×	×		○	○	○	○

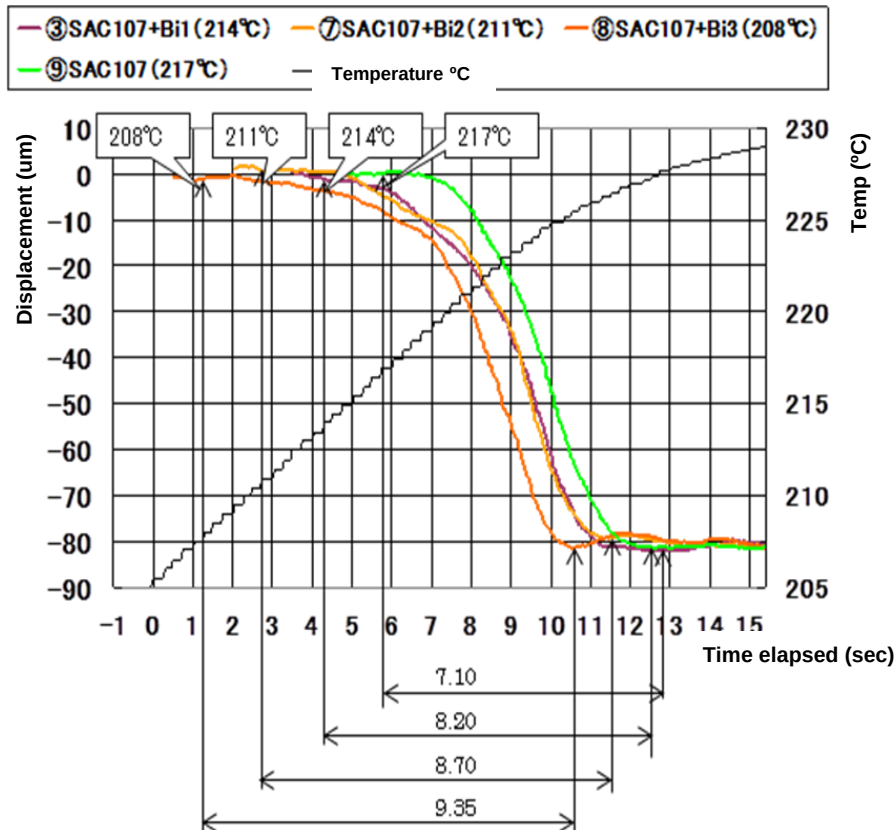
Wetting Test

Displacement wetting test by profile heating

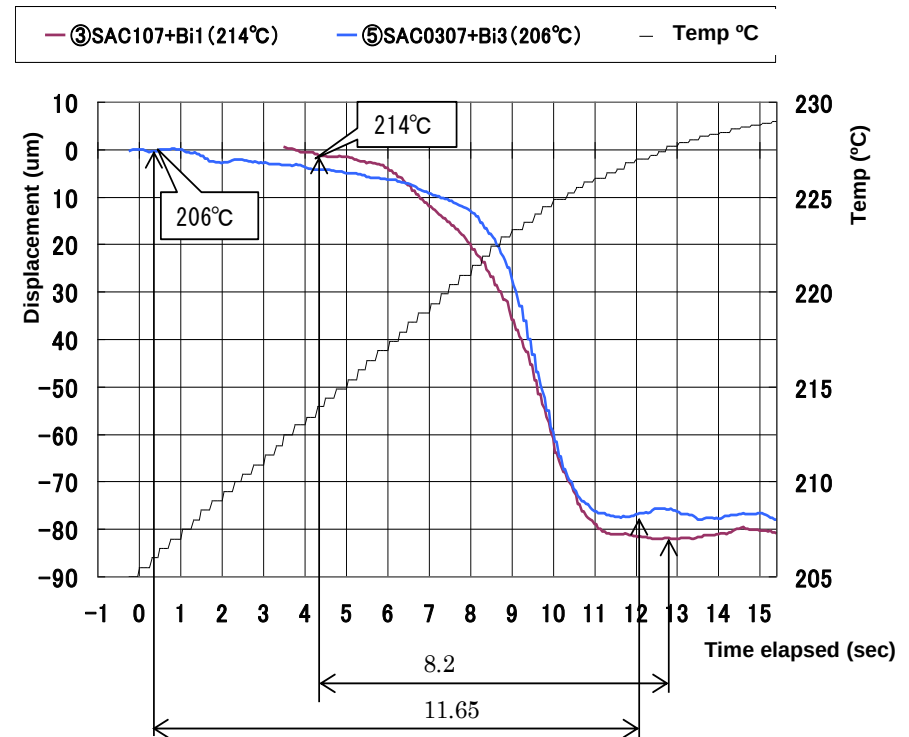
- Possible to compare wetting values using Cu coupon
- Possible to measure the temp & time at the start and the completion of wetting



Wetting Test Results



	Composition	Solidus (°C)	Liquidus (°C)	t2 (sec)	Wetting time
③	SAC107+Bi1	214	223	8.20	2:45.7
⑦	SAC107+Bi2	211	221	8.70	2:44.0
⑧	SAC107+Bi3	208	221	9.35	2:43.7
⑨	SAC107	217	224	7.10	2:46.1

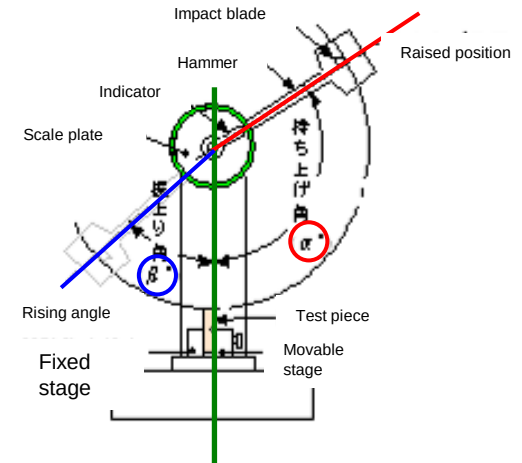
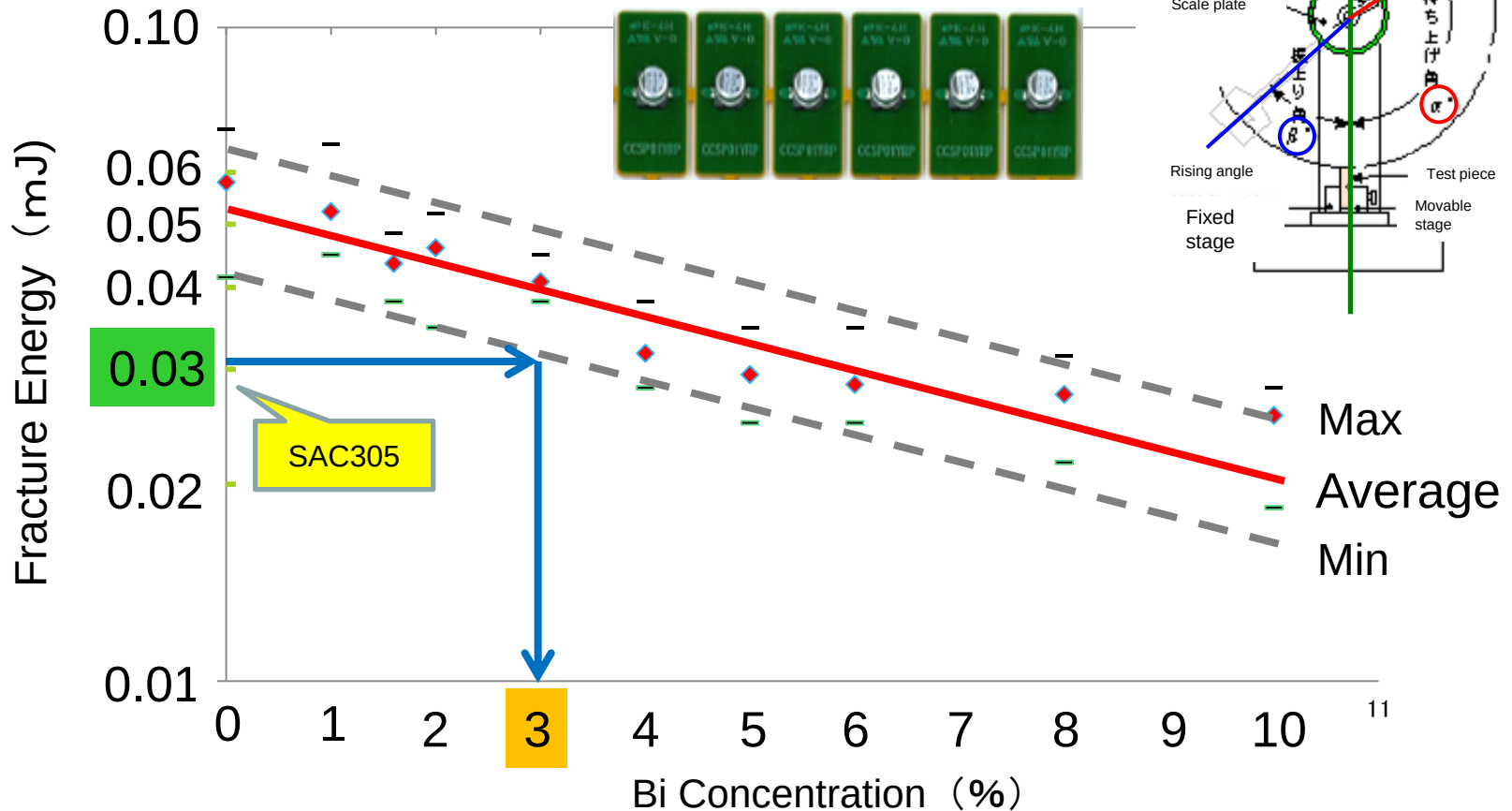


	Composition	Solidus (°C)	Liquidus (°C)	t2 (sec)
③	SAC107+Bi1	214	223	8.20
⑤	SAC0307+Bi3	206	222	11.65

Mechanical Strength Test

The Effect of Bi using Izod Impact Test

Component : Dia. 5mm Cap Aluminum (Nichicon UWT1C220MCR1GB)
Solder Paste : SAC (Ag0.3, Ag1.0, Ag3.0 wt%)

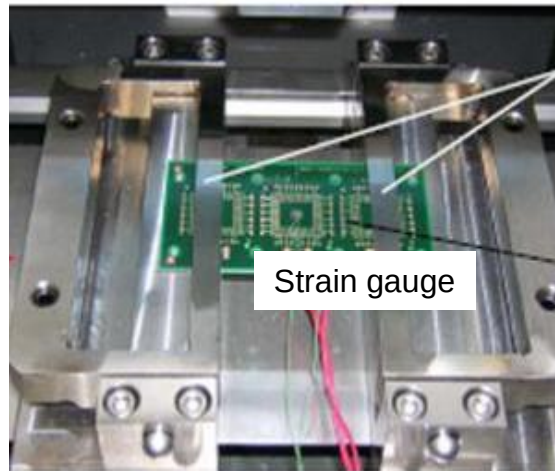


To meet SAC305 level, Bi content in SACB107 α must be **3wt% Max**

Substrate Bending Test (Rod Drop)

(ED-4702B)

Rod Drop Impact Test : Impact Bending Test (IBT)



<Board>

Material : FR4

Pad : Cu-OSP

Outline : 30x120x1.6mmt

<Sample>

BGA : 1313-224 pins(0.5mP)

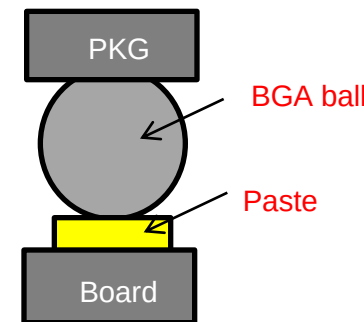
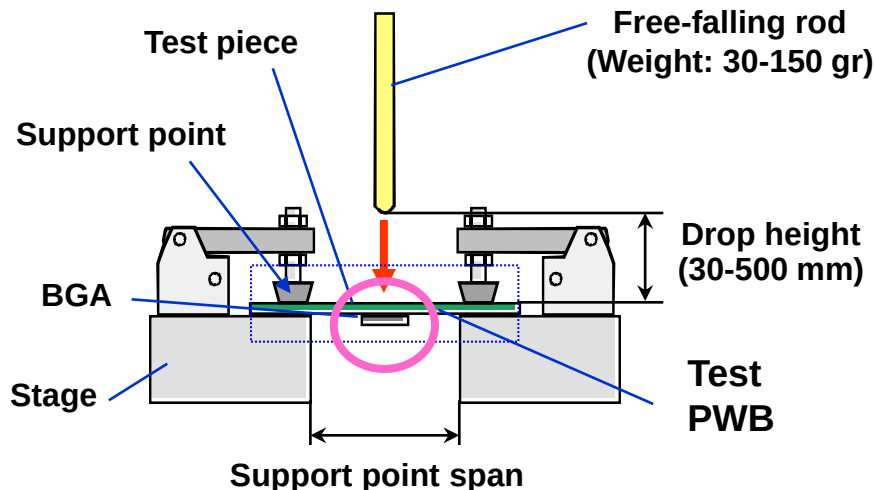
PKG pad : Electrolytic Ni/Au

Ball alloy: SAC305 &SAC105

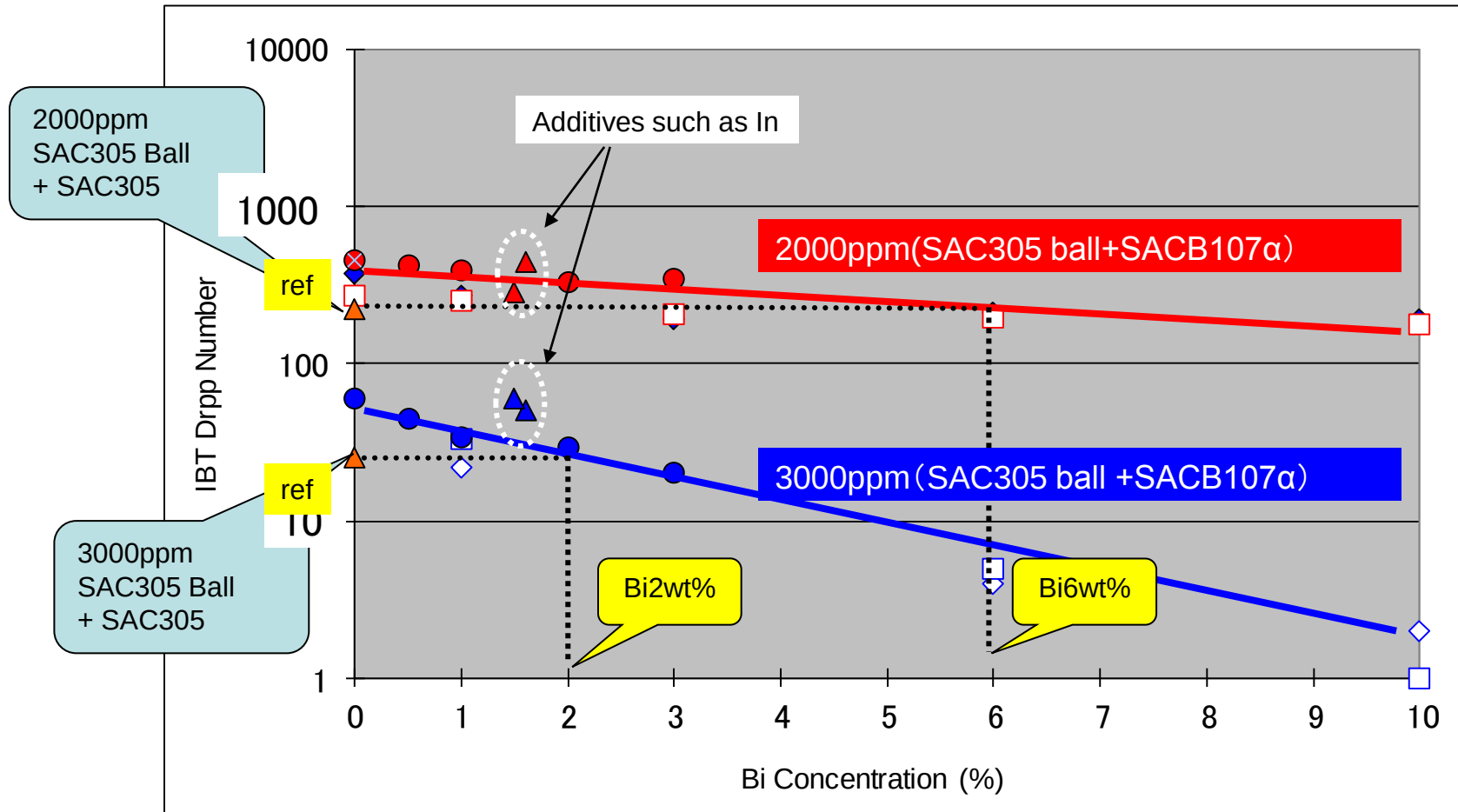
Ball dia : 0.3mm

<Reflow Profile>

Peak 235°C



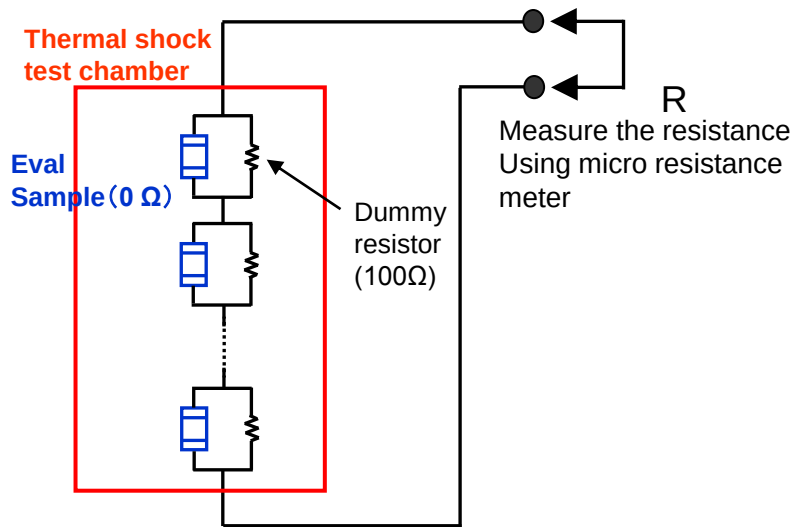
IBT Evaluation Results



- (1) For SAC305 ball & SACB107 paste combination, SAC305 equivalent level can be met when Bi is 6% for IBT (2000ppm) and 2% for IBT(3000ppm).
- (2) For high-impact IBT (3000ppm), additives such as In are found to be effective.

Thermal Fatigue Test

Overview of Thermal Fatigue Test



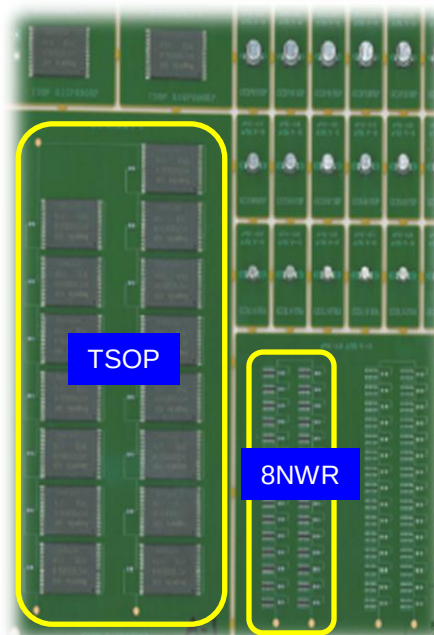
Test Conditions:
-25°C ~125°C (20min/cyc) 1500 cycle

Connect evaluation sample & dummy resistor (1608 size 100Ω) in parallel,
then connect n=30 in series

If open is found in one sample, detect the 100Ω of dummy resistor

By using micro meter, detect the change in resistance and determine the cycle
where cracks had occurred (electrical opens)

Perform Weibull analysis and compute the cycle numbers at 1% cumulative
failure rate

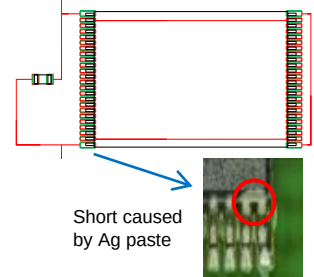


Components:

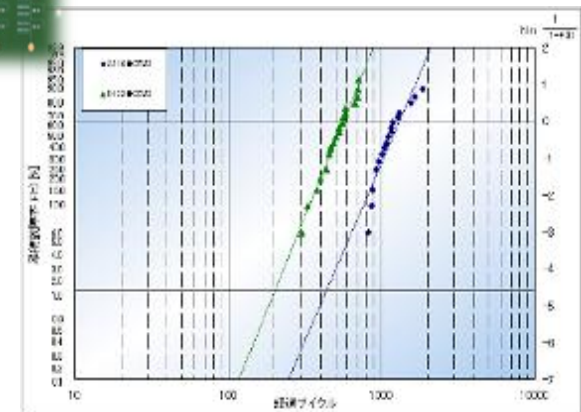
(1) Eight-ganged network resistor (8NWR)



(2) TSOP



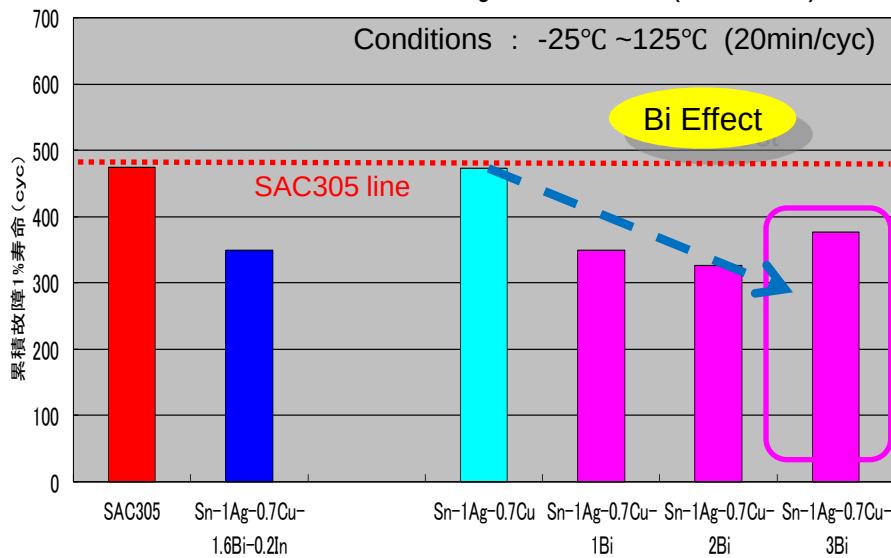
Board : FR-4
Size : 160
x16mm
Thickness : 1.6mm
Screen thickness : 120μm



Test result example

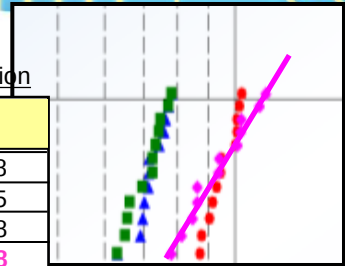
Thermal Fatigue Test Results (8NWR)

8NWR Thermal Fatigue Test Results (Effect of Bi)

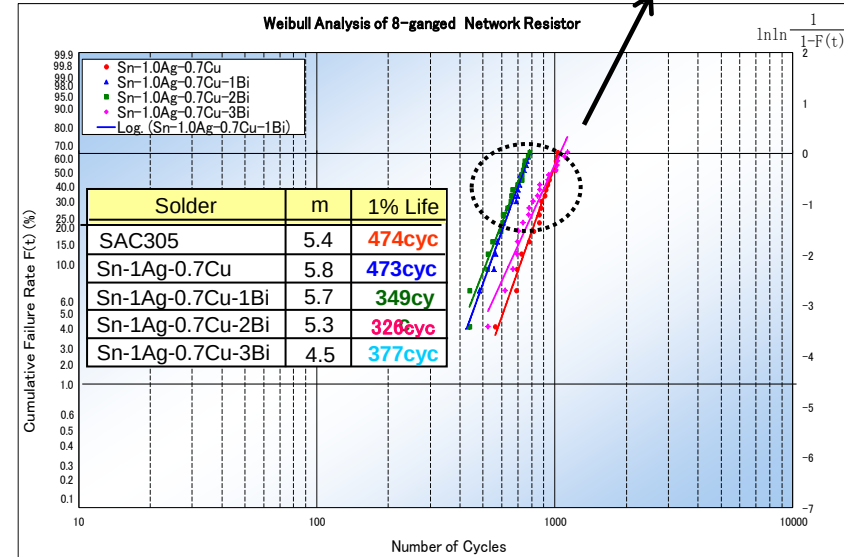


m values in the failure region

Solder	m
Sn-1Ag-0.7Cu	5.8
Sn-1Ag-0.7Cu-1Bi	6.5
Sn-1Ag-0.7Cu-2Bi	4.8
Sn-1Ag-0.7Cu-3Bi	2.8



Weibull Analysis of 8-ganged Network Resistor



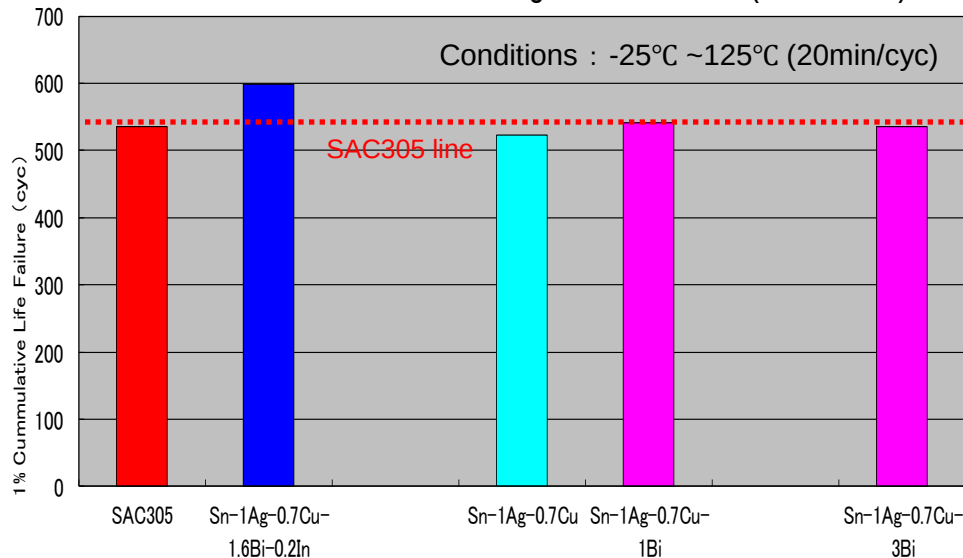
- Thermal fatigue life of Sn-1Ag-0.7Cu is similar* to that of SAC305
- The life of Sn-1Ag-0.7Cu drops by 20~30% when 1~3% of Bi is added.

※ As compared to Bi1% & Bi2%, the Weibull slope of Bi3% is different and therefore the failure mode is likely to be different

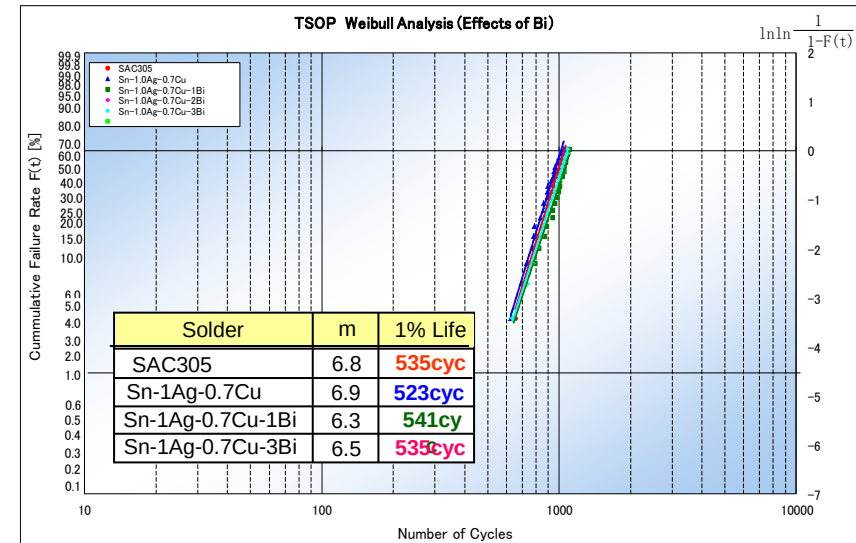
*Definition of "similar" : Nearly the same Weibull slope & cycle # at 1% cumulative failure rate is within ±10%

Thermal Fatigue Test Results (TSOP)

TSOP Thermal Fatigue Test Results (Effect of Bi)



- Thermal fatigue life of Sn-1Ag-0.7Cu is similar to that of SAC305
- Life of Sn-1Ag-0.7Cu similar when 1% & 3% Bi are added
⇒ Same results as previous small quantity testing
- Slight increase in life for Sn-1Ag-0.7Cu-1.6Bi-0.2In as compared to SAC305 (by 10%)



Previous test results Conditions: -40°C ~125°C (60min/cyc)

Base Solder	B content (%)	200cyc	400cyc	600cyc
Sn-1Ag-0.7Cu	0	0/3 NG	0/3 NG	2/3 NG
	3	0/5 NG	0/5 NG	1/5 NG
	5	0/5 NG	3/5 NG	5/5 NG
	8	0/5 NG	4/5 NG	5/5 NG
	10	0/5 NG	5/5 NG	5/5 NG

Dramatic drop in life when Bi is added by 5% or more

Summary & Conclusion

■ Selection of low-Ag SAC alloy

Based on the Phase 2 evaluation results, Sn-1Ag-0.7Cu-2Bi is the recommended alloy for the low-Ag alternative.

Both Sn-0.3Ag-0.7Cu & Sn-1.0Ag-0.7Cu are potential candidates for the alternative alloy. However, the lowest allowable heating temp is the major weakness of these alloys. According to the test results, when the peak temp is set at 230°C the following can be summarized against the melting temp limit.

- 1 . The current SAC305 has a margin of $5^{\circ}\text{C} + \alpha$
- 2 . SAC107 has no margin at the lower limit
- 3 . SAC107 + 2%Bi ensures a margin of 5°C

■ Low-temp and specialized alloys

This project has been suspended because industry-wide standard alloy cannot be identified. We look forward to the developmental activities by others.